

THERESA (TeraHErtz REadout Sampling)

A Terabit sampling system with a photonics time-stretch ADC

Olena Manzhura

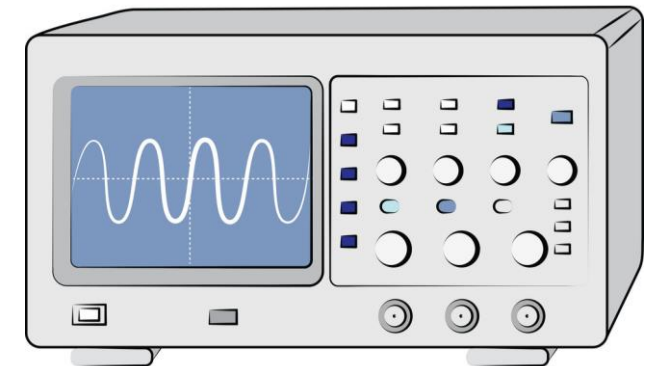
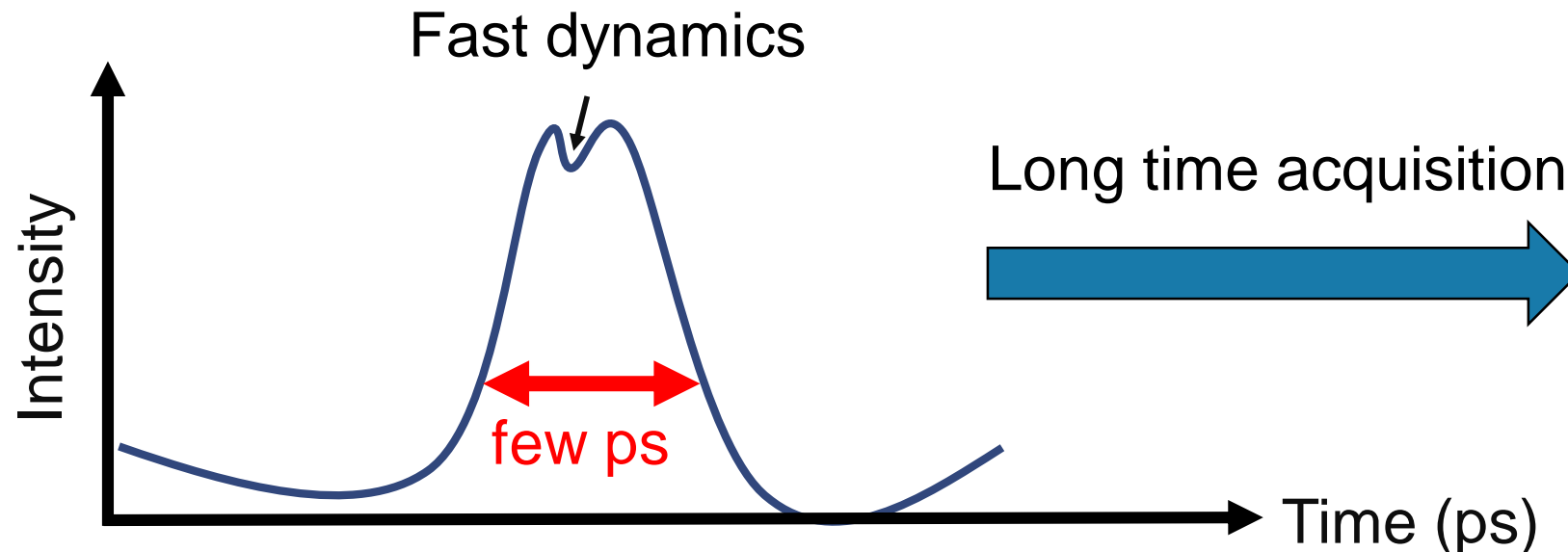
Advisor: *Prof. Anke-Susanne Müller*

Scientific advisor: *Dr. Michele Caselle*

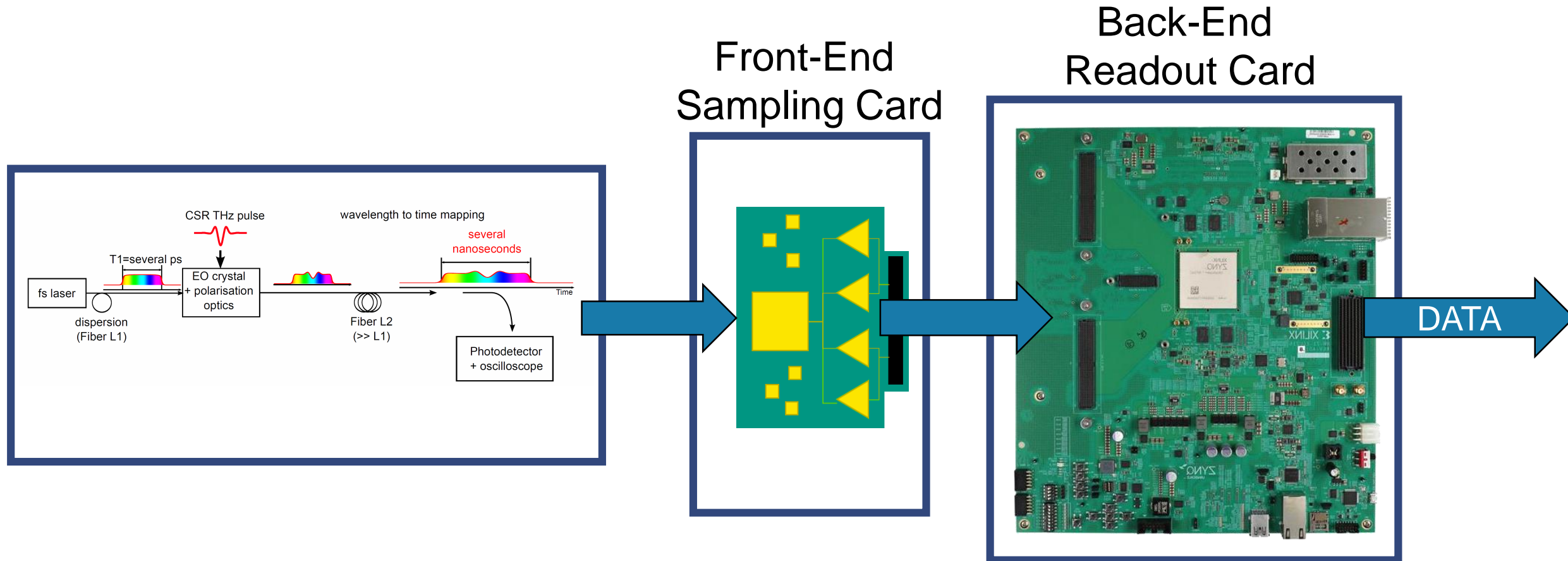


Motivation: Realizing Ultra-Fast Measurements

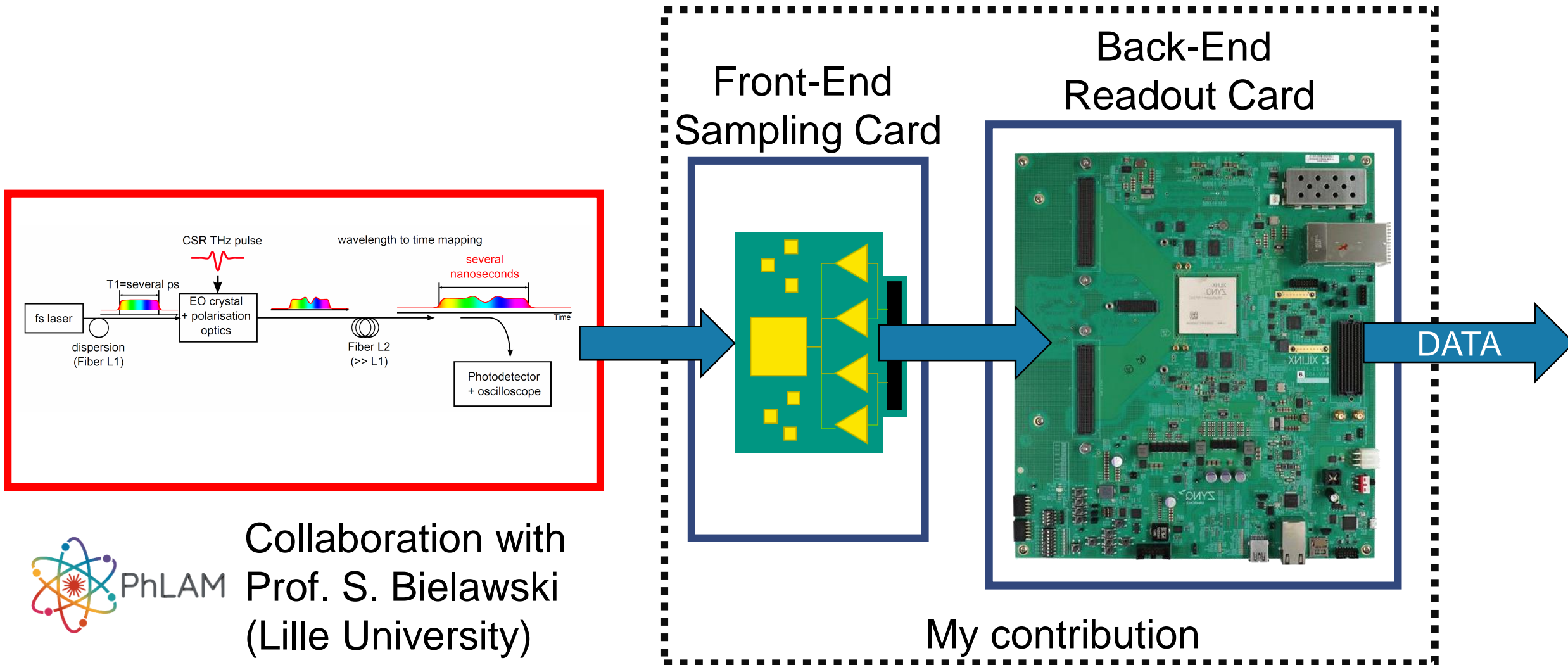
- Study of complex dynamics is crucial for understanding numerous physical processes (e.g. in beam diagnostics, laser dynamics, ...)
- Time scale of dynamics: 10 fs to hundreds of ps
- Long time continuous acquisition (1 s to several hours) required



THERESA (TeraHertz REadout SAmpling)

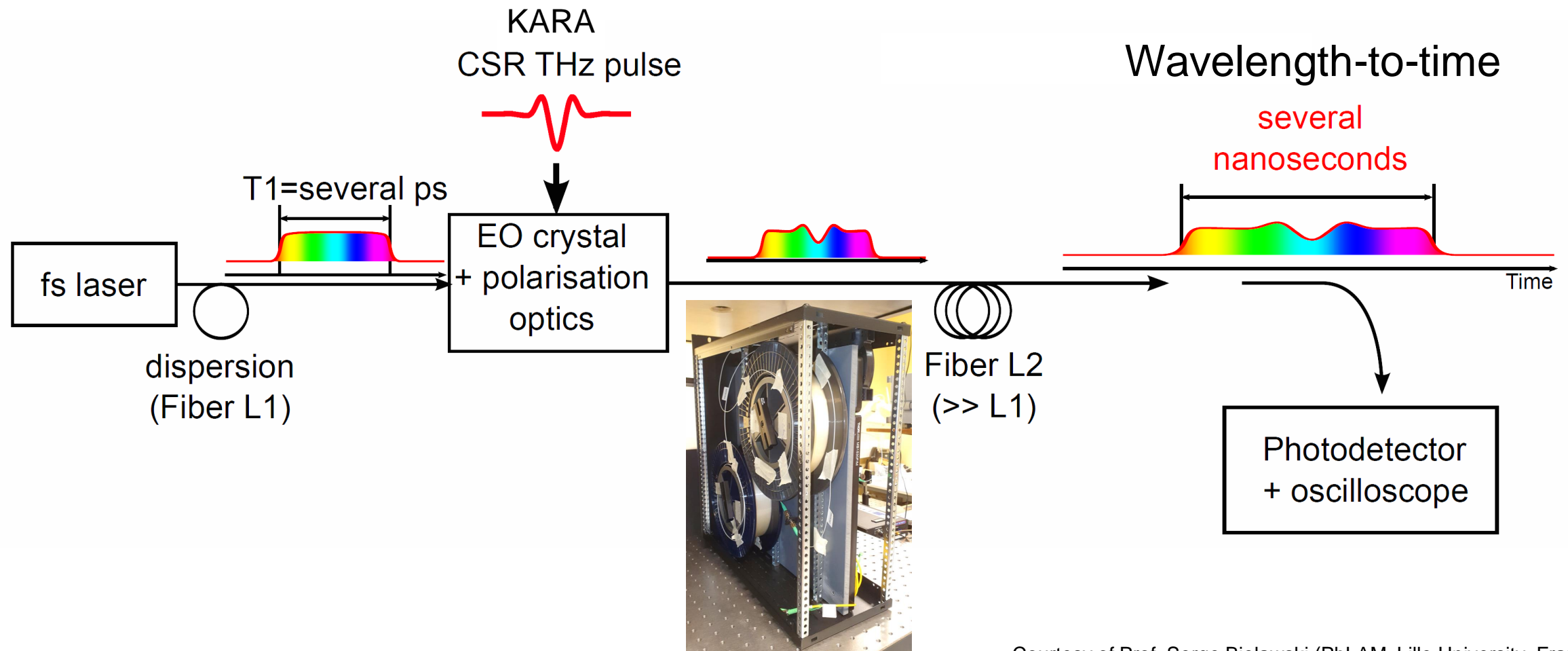


THERESA (TeraHertz REadout SAmpling)



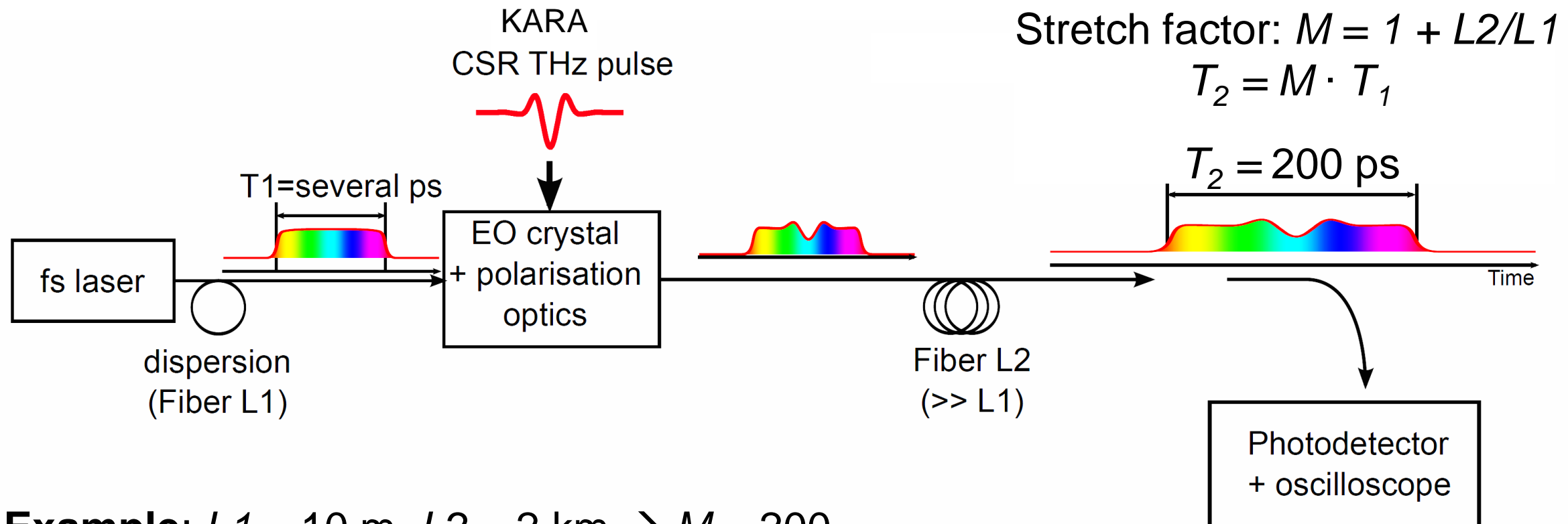
Collaboration with
Prof. S. Bielowski
(Lille University)

Photonic Time-Stretch Method



Courtesy of Prof. Serge Bielawski (PhLAM, Lille University, France)

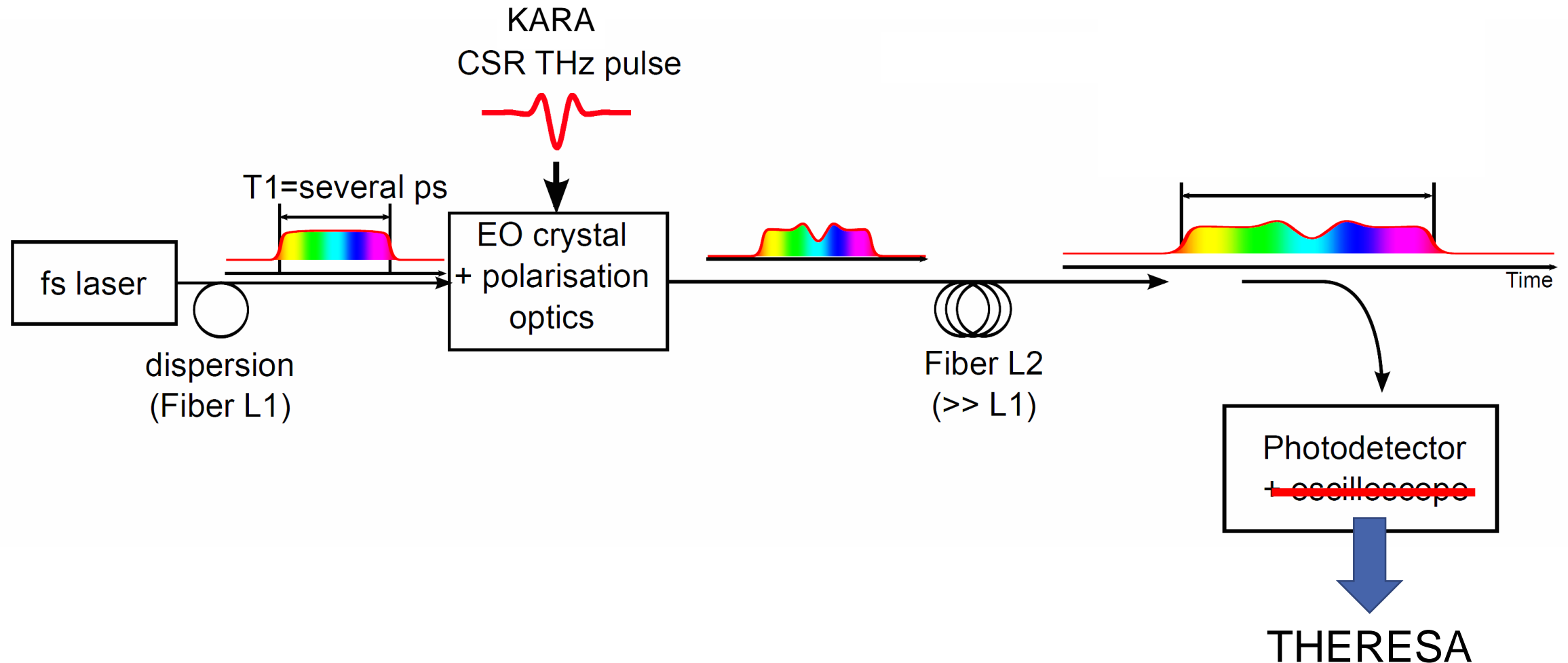
Photonic Time-Stretch Method



Example: $L_1 = 10 \text{ m}$, $L_2 = 2 \text{ km} \rightarrow M = 200$

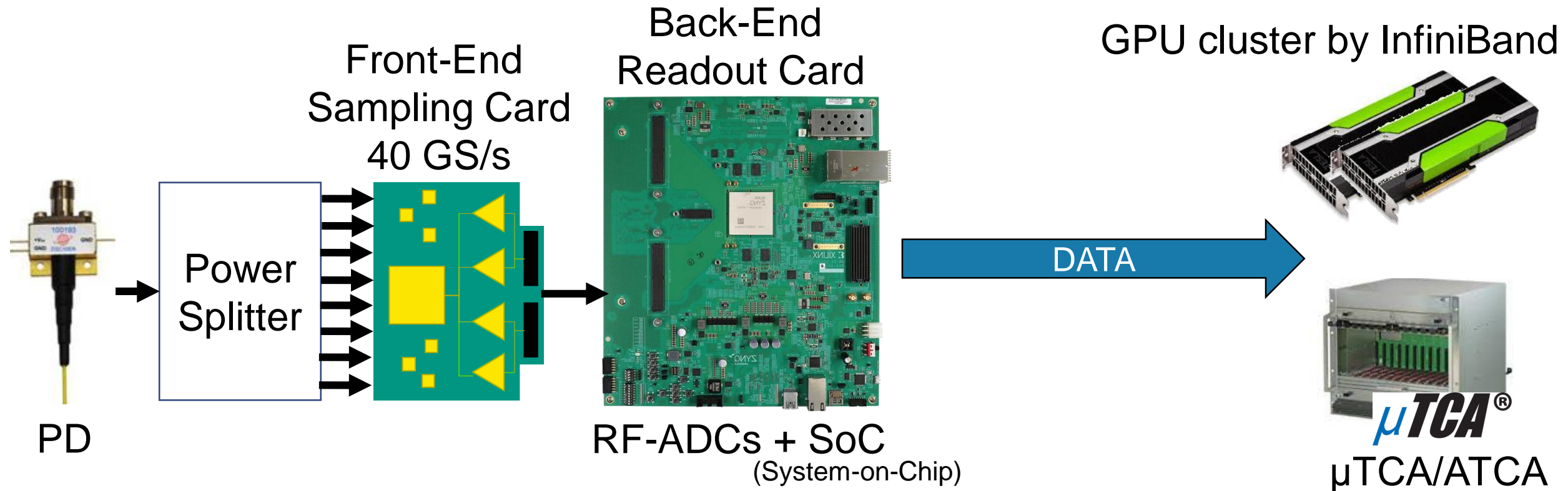
$T_1 = 1 \text{ ps} \triangleq 1 \text{ THz} \rightarrow T_2 = 200 \text{ ps} \triangleq 5 \text{ GHz}$

Photonic Time-Stretch Method

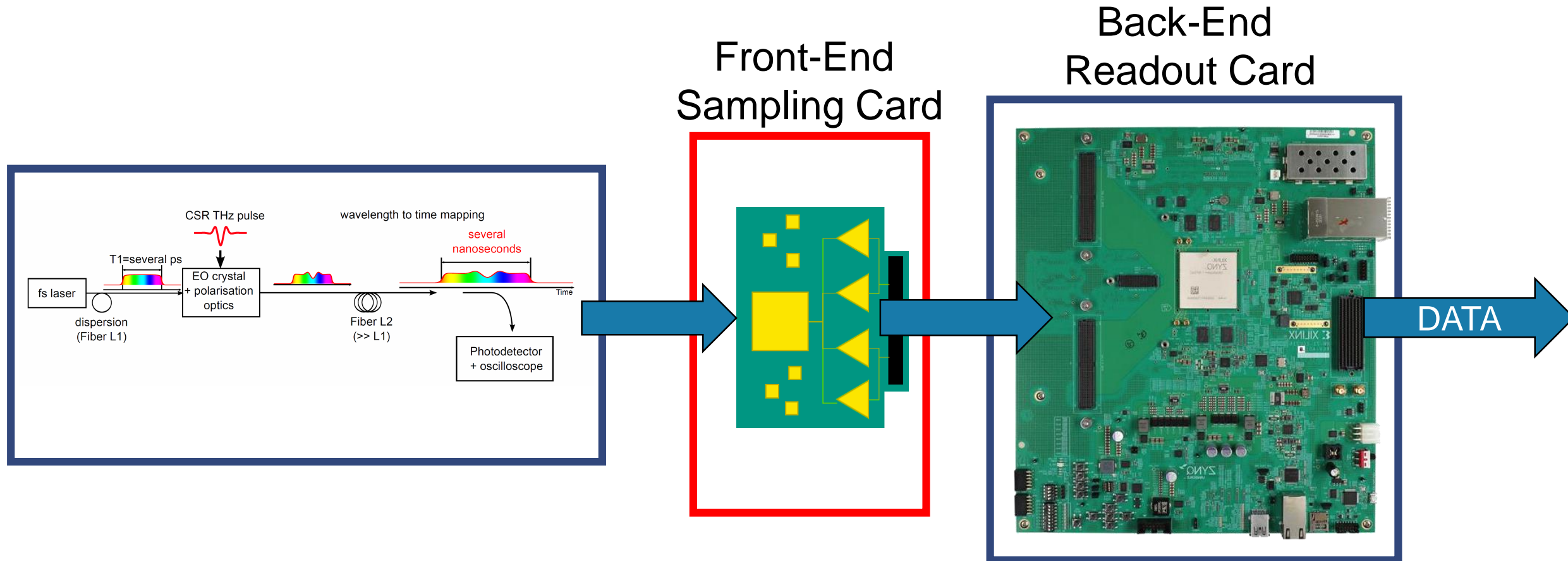


Thesis Objective

- Design a DAQ system, operating in continuous acquisition mode, to sample the photodetector (PD) signal and overcome memory limitation

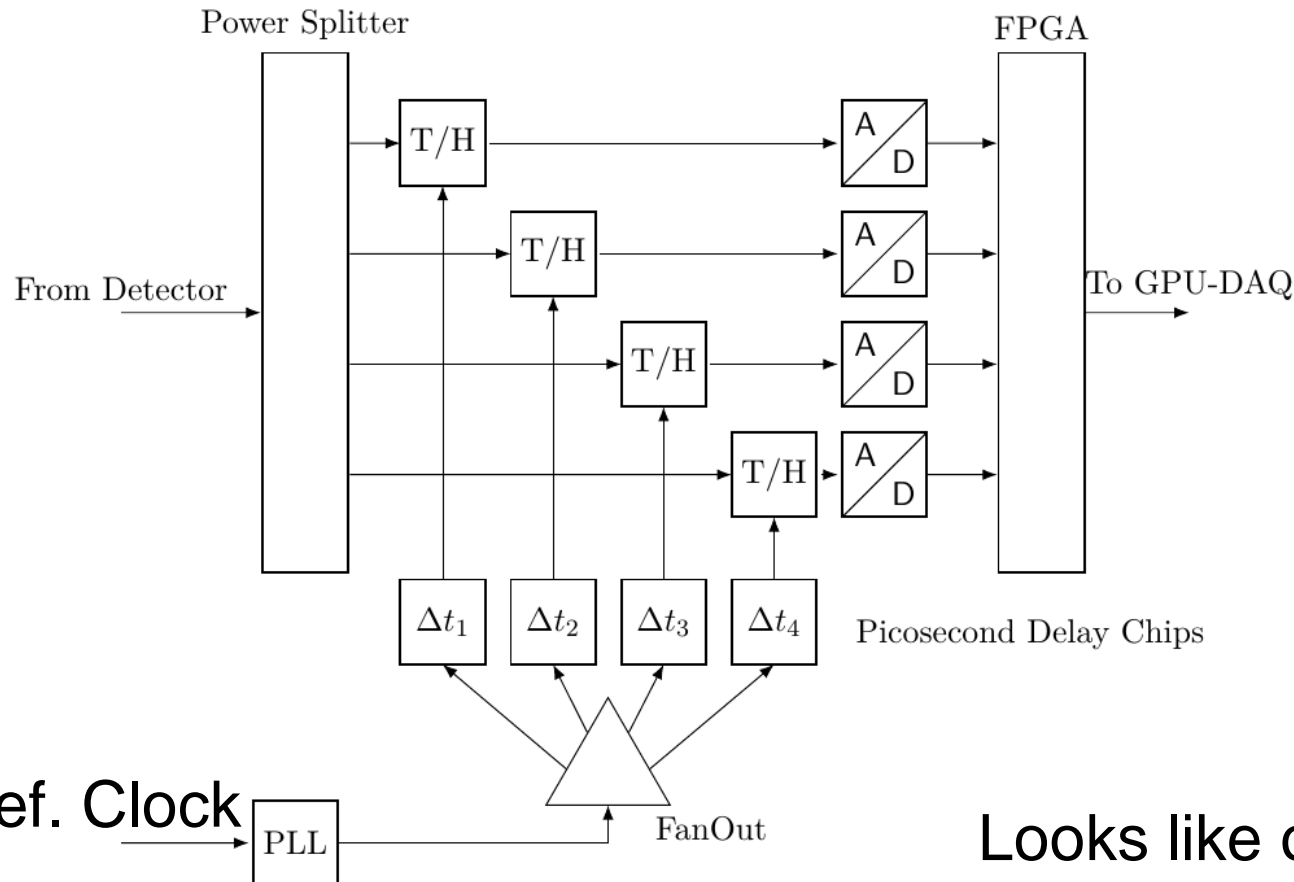


THERESA (TeraHertz REadout SAmpling)

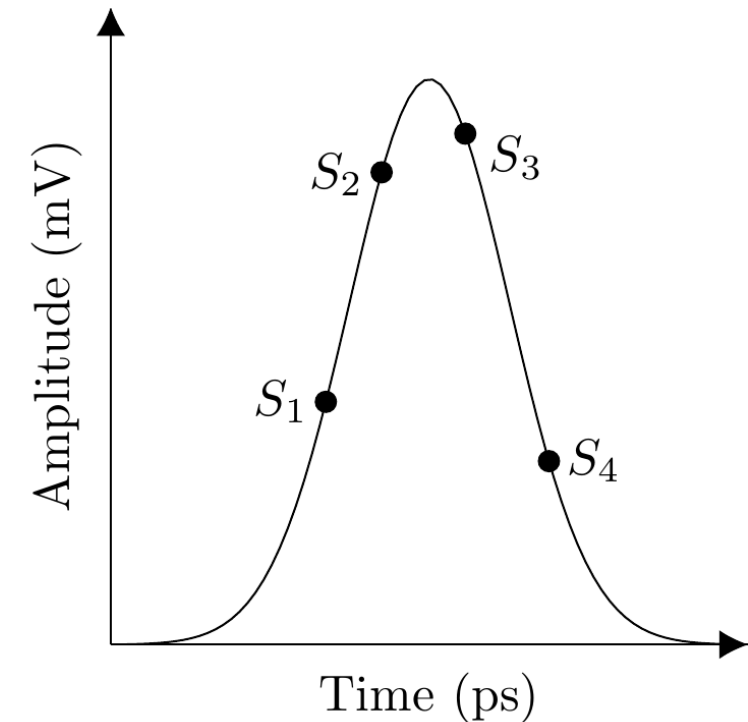


Sampling Concept: Programmable Time Delay

KAPTURE Concept



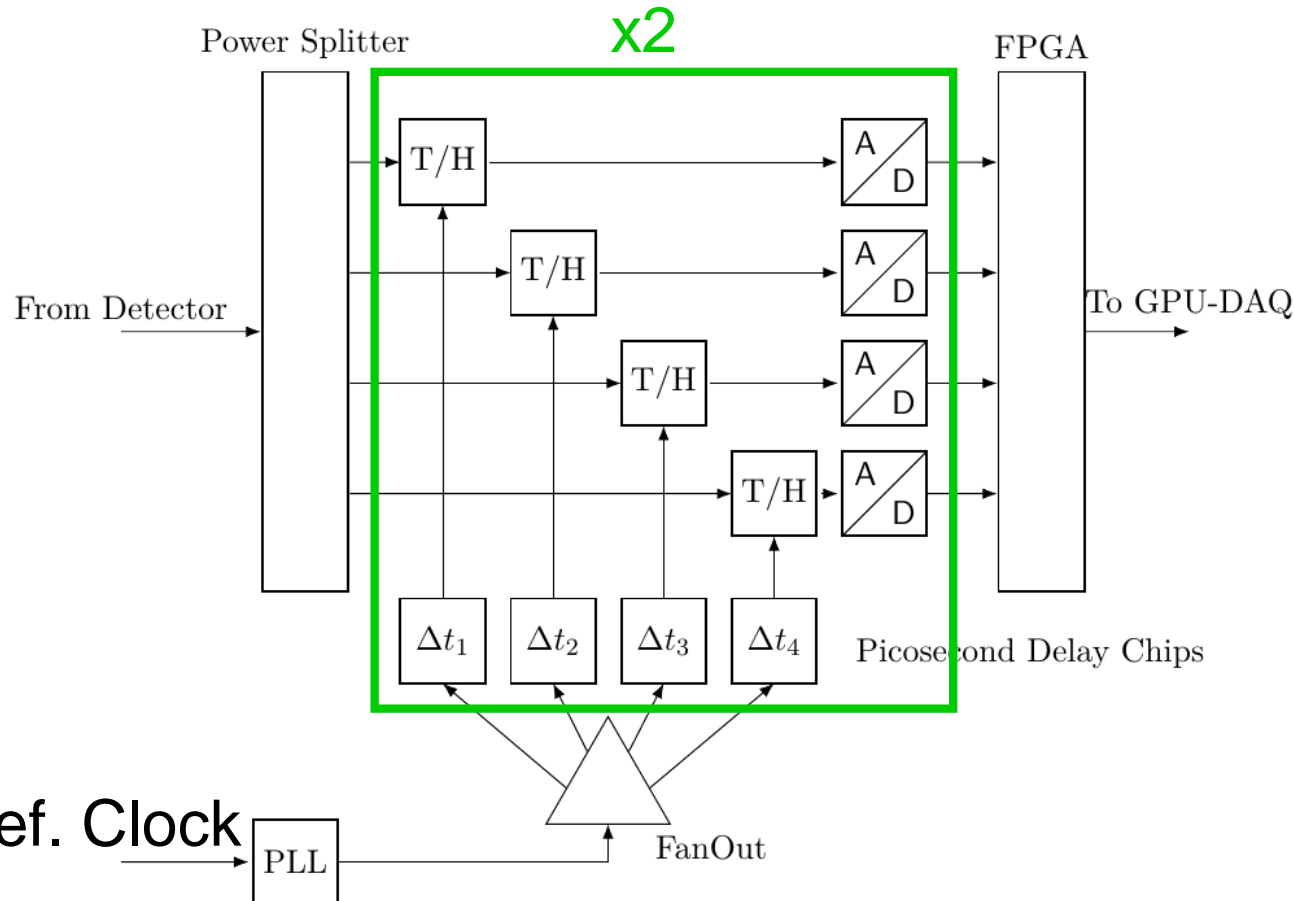
4 Samples



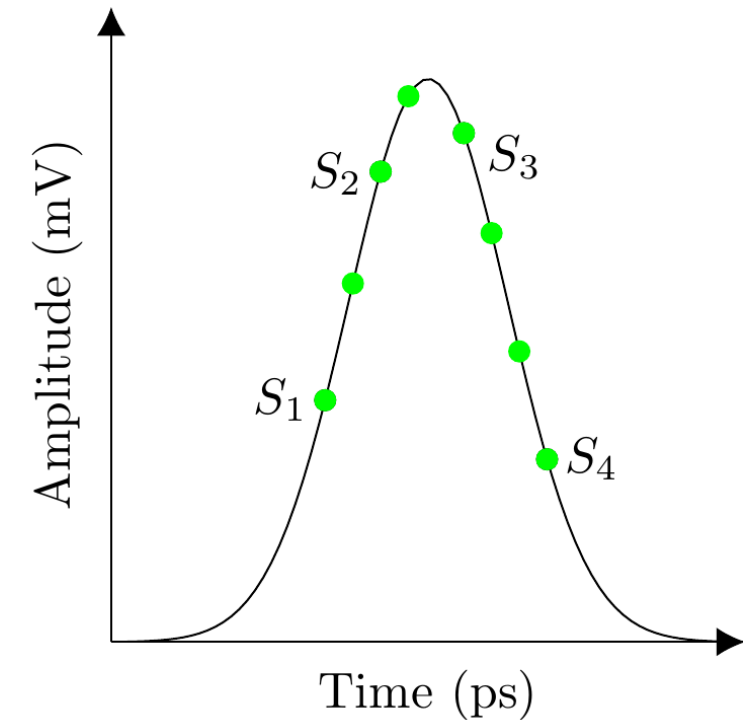
Looks like one ADC sampling at fast sample rate

Sampling Concept: Programmable Time Delay

KAPTURE v2 Concept

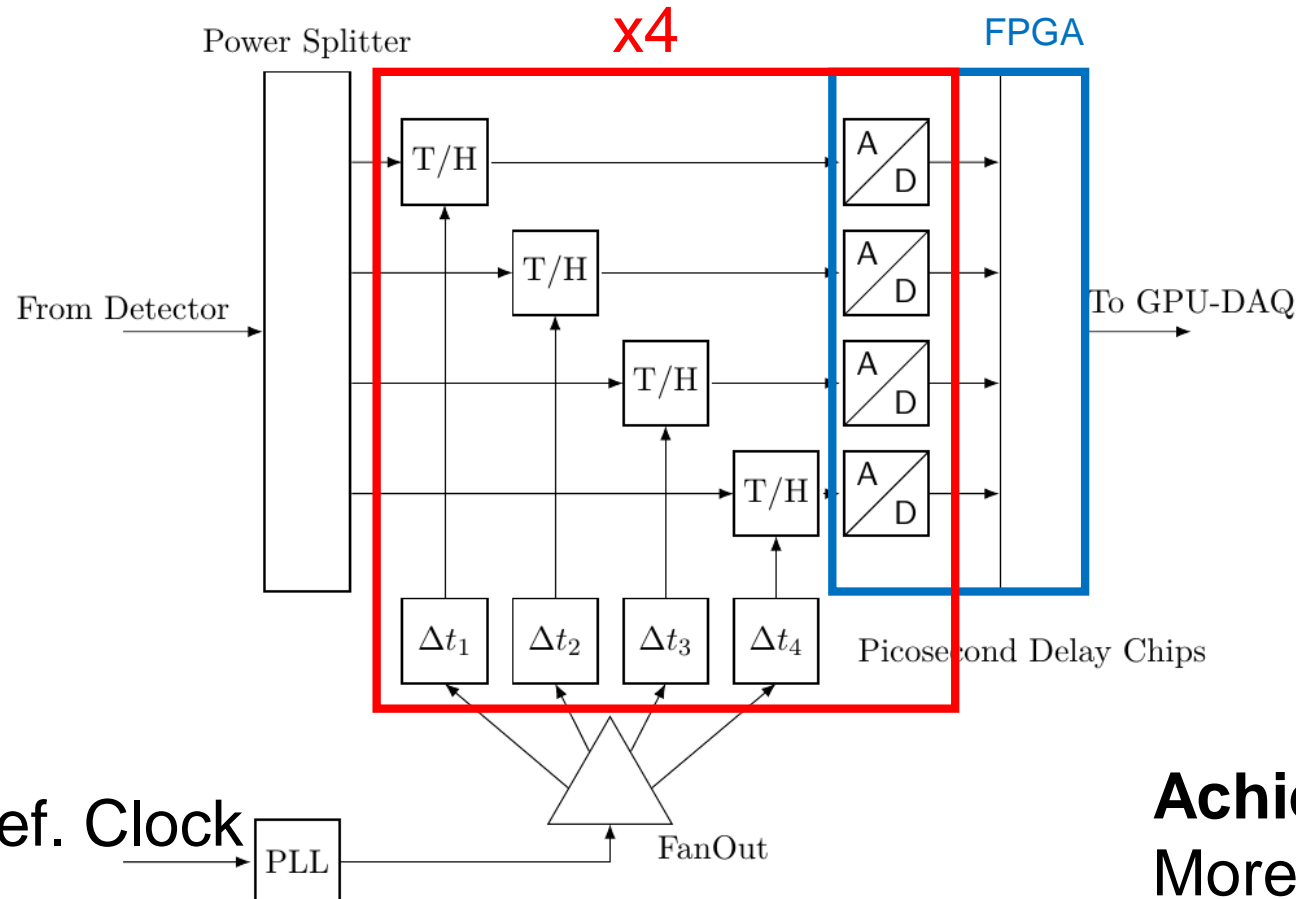


8 Samples

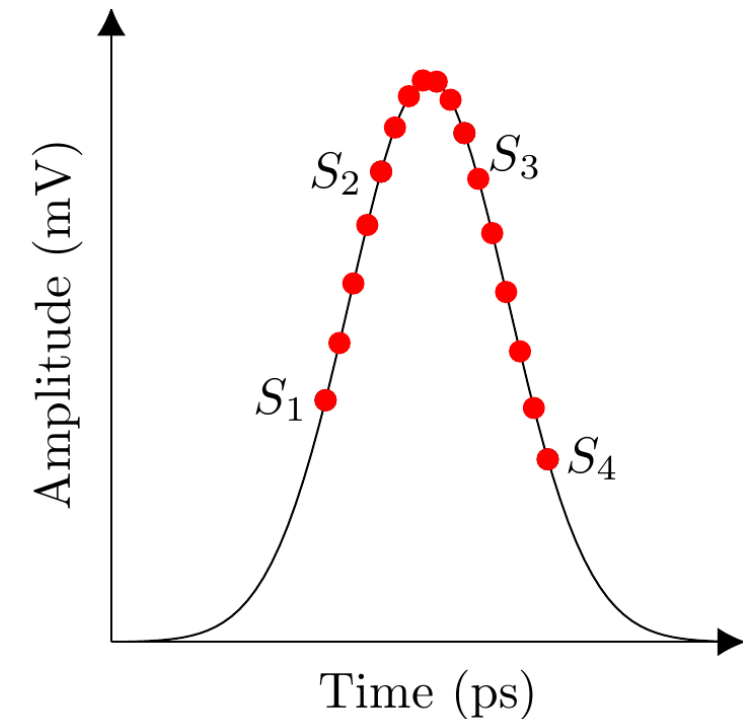


Sampling Concept: Programmable Time Delay

THERESA Concept



16 Samples



Achievements:

More samples + reduced board complexity

Characteristics of THERESA

Features	KAPTURE v2	THERESA
# Channels	8	16
Sampling rate per channel	1.8 GS/s per channel	2.5 GS/s per channel
Max. sampling rate (time-interleaved)	4 channels: up to 7.2 GS/s 8 channels: up to 14.4 GS/s	Up to 40 GS/s (16 x 2.5 GS/s)
Operation modes	<ul style="list-style-type: none"> • Single channel → 1 sample/channel • Multiple sampling points (up to 8) 	<ul style="list-style-type: none"> • Photonic Time-Stretch ADC (TS-ADC)
Expected time resolution	3 ps	125 fs (e.g.: stretch factor M=200)
Delay range	3 - 100 ps (→ not suitable for time-stretch)	0 - 11.2 ns (with 511 programmable steps)

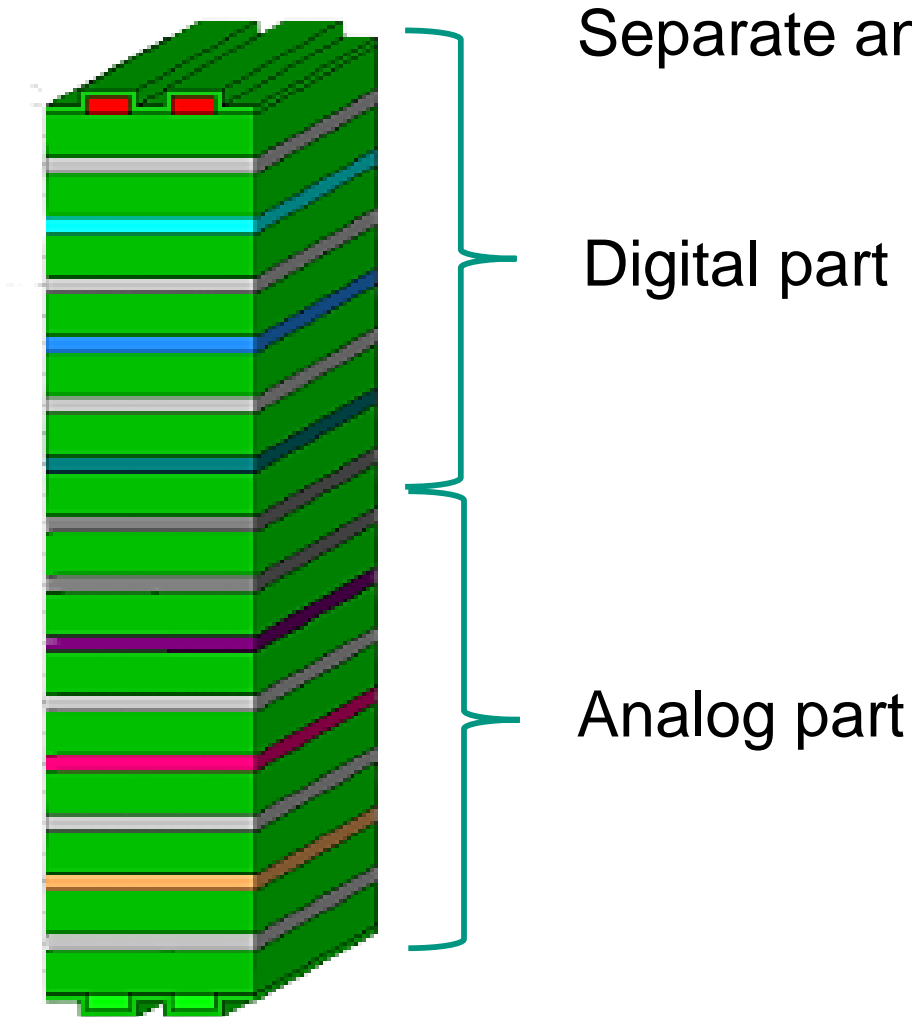
Design Challenges in Front-End Card

- Wide bandwidth (Track-and-Hold-Amplifier(THA) limits to 18 GHz)
- Very low-noise conditions (THA limits to 60 dB SINAD¹, ENOB² \approx 10 bits)
- HF PCB dielectric, metal layer stack-up, RF components/filters, impedance matching, etc.
- High-speed and time skew controlled transmission lines
- Slow-control and calibration circuits

¹ Signal-to-Noise-and-Distortion ratio

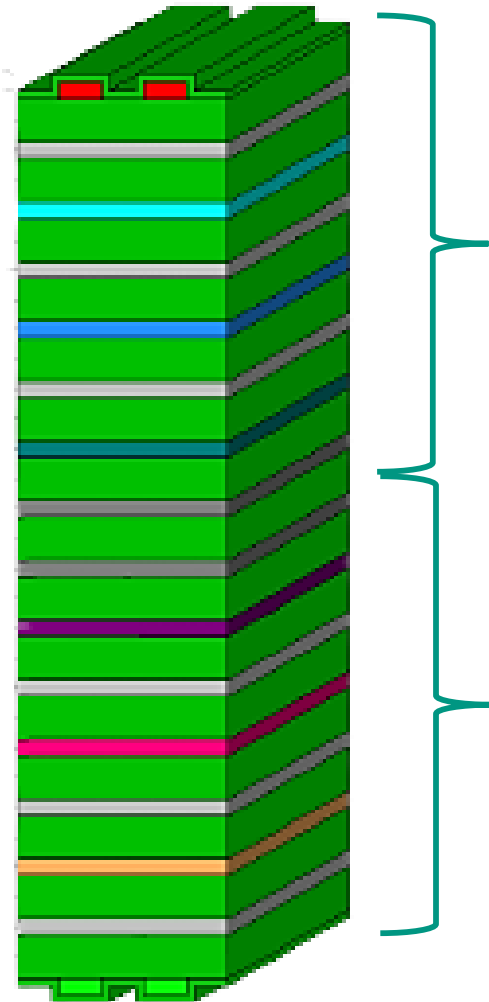
² Effective-Number-of-Bits

PCB Design : Substrate & Metal Layer Stackup



PCB Design : Substrate & Metal Layer Stackup

Separate analog from digital:

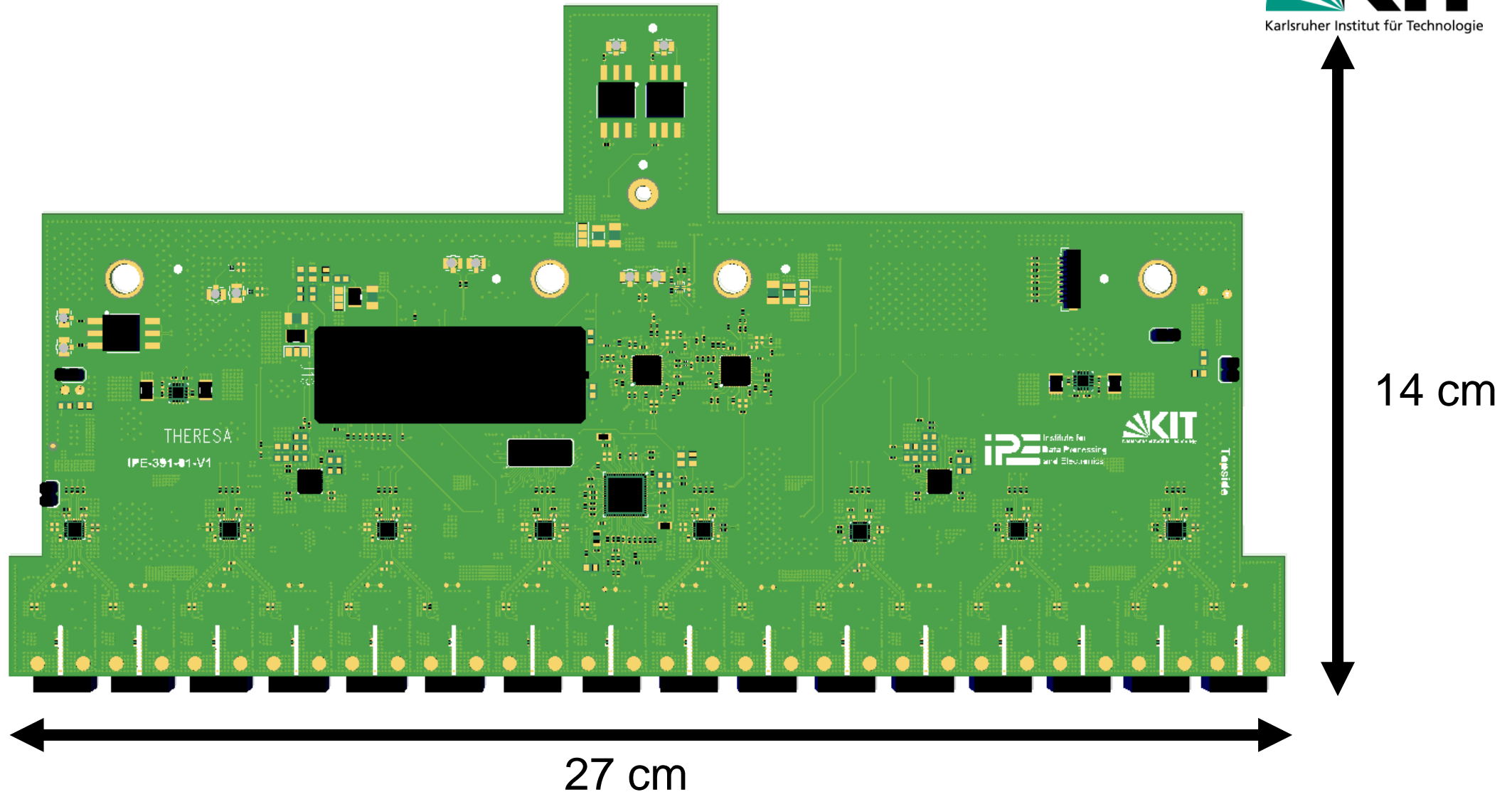


Digital part:

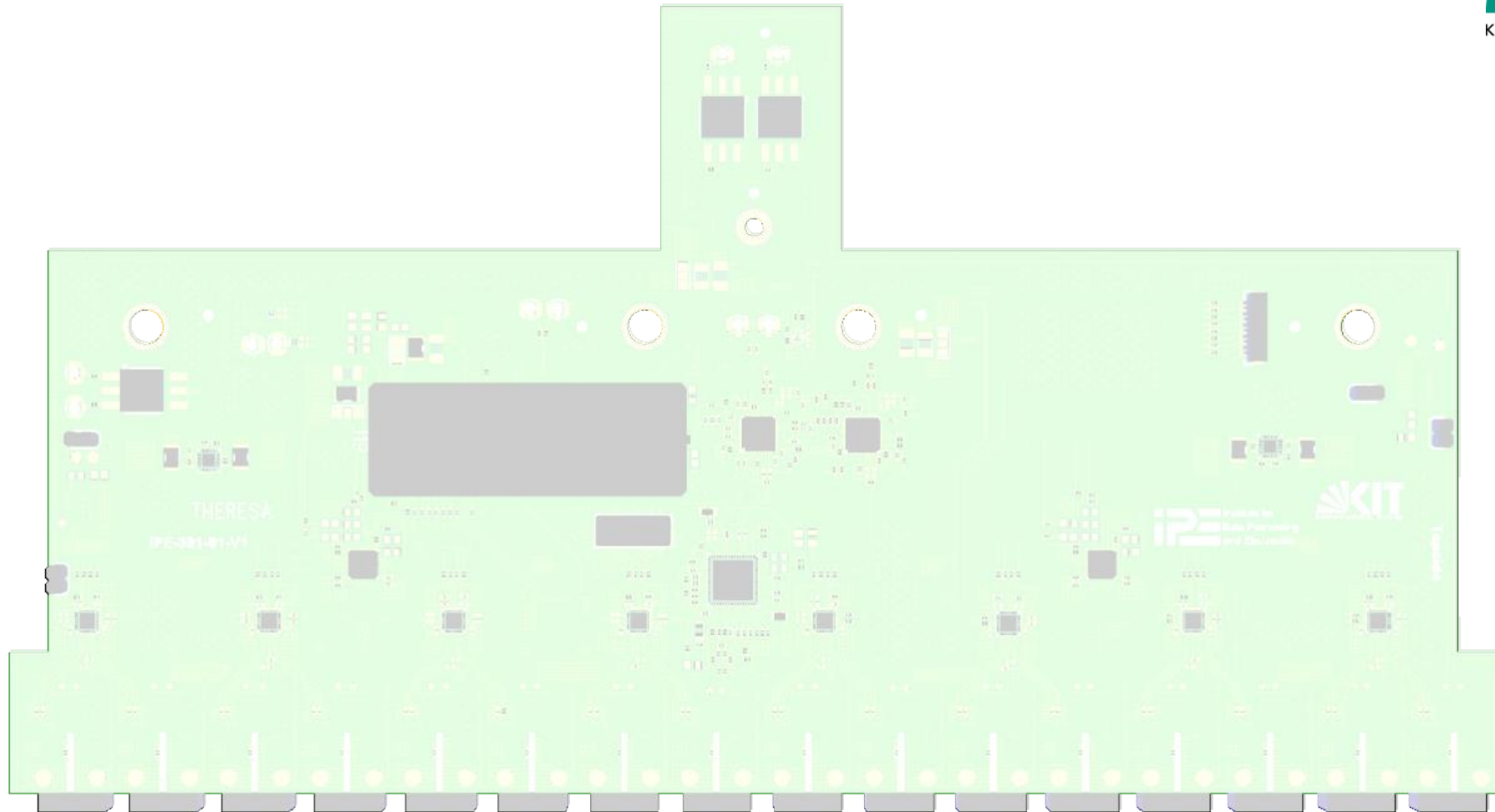
- Clocking distribution
- Delay chips
- Slow control lines

Analog part

Digital Component Placement (Top)

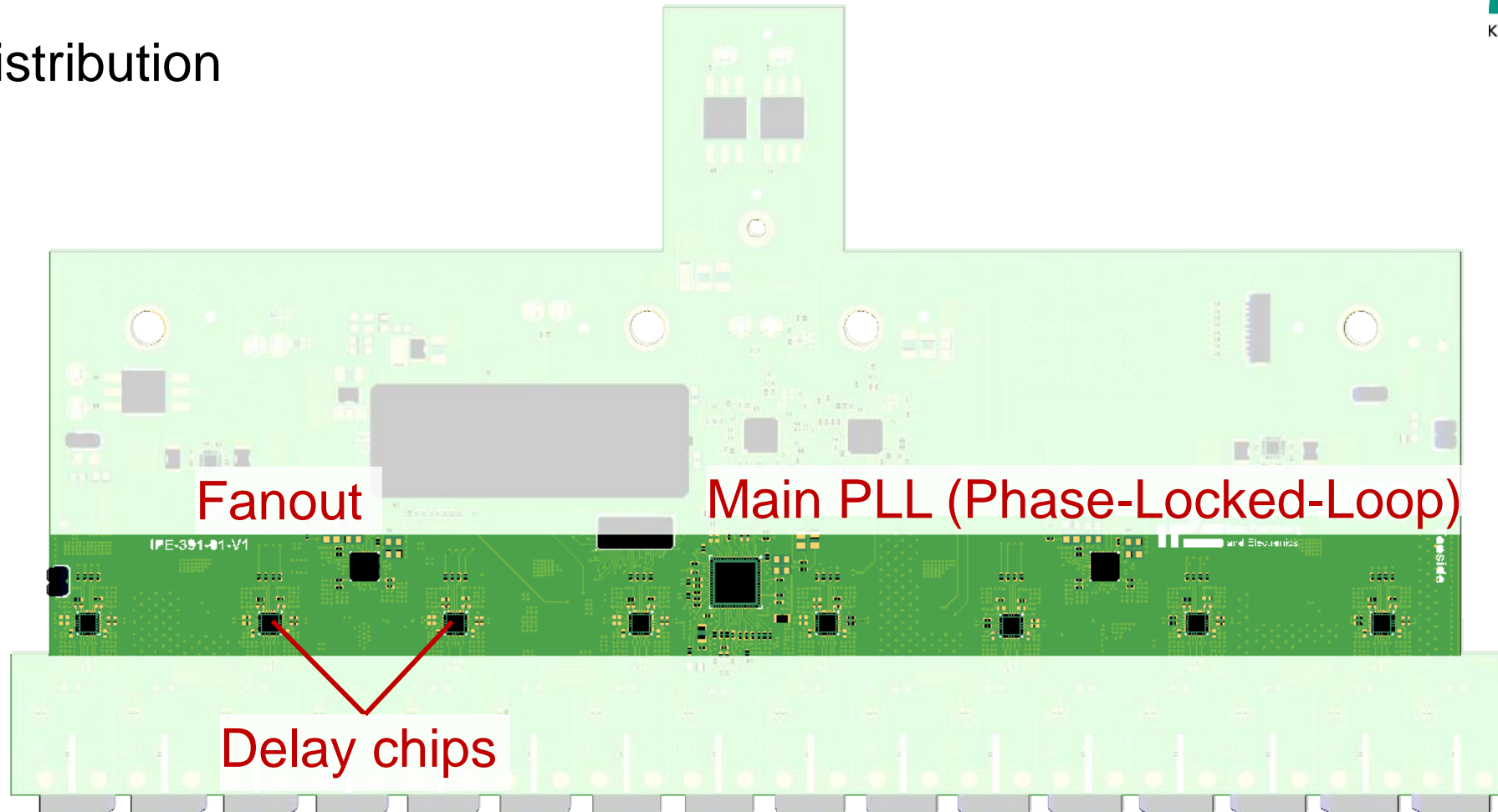


Digital Component Placement (Top)



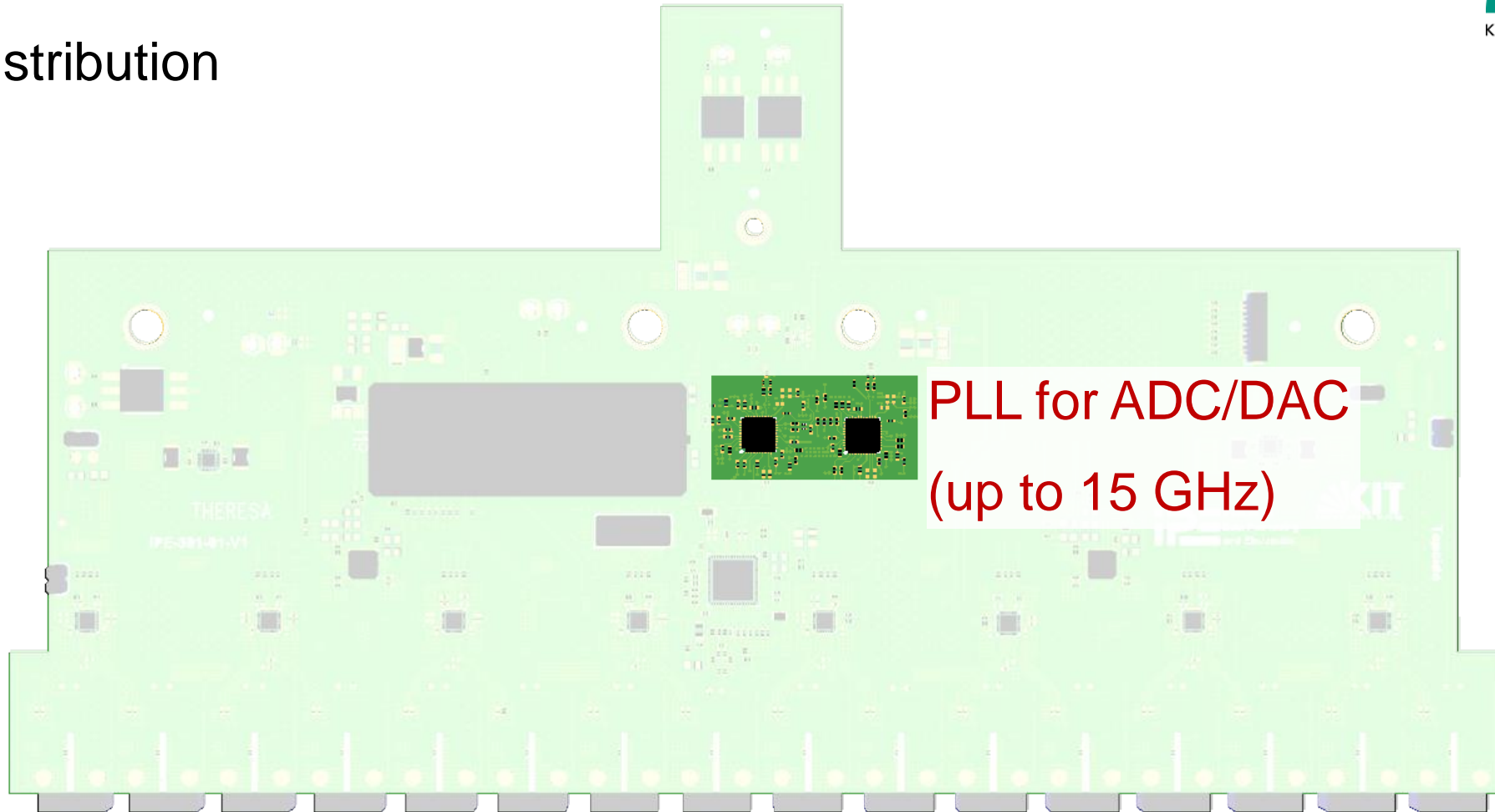
Digital Component Placement (Top)

Clock Distribution

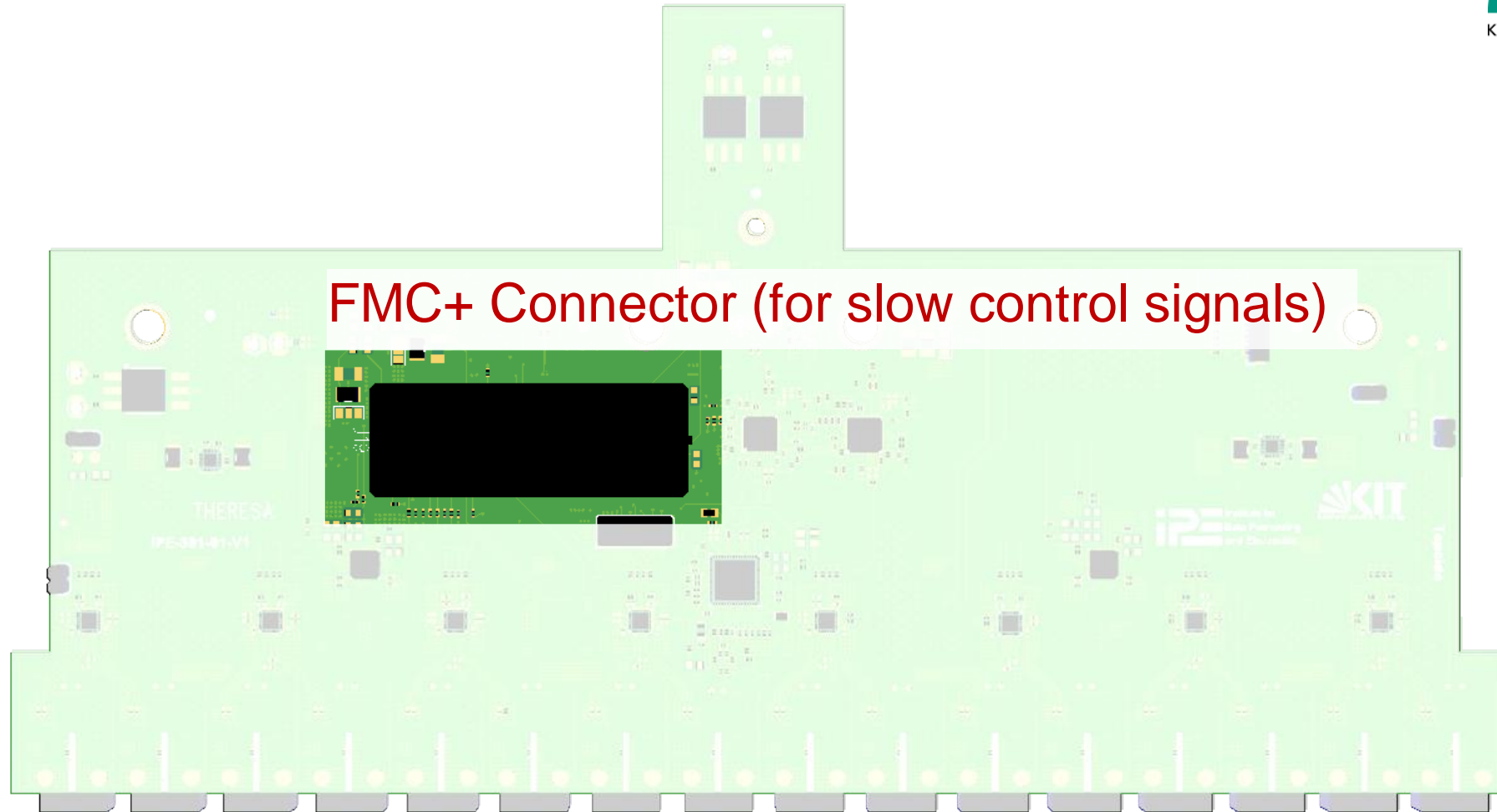


Digital Component Placement (Top)

Clock Distribution

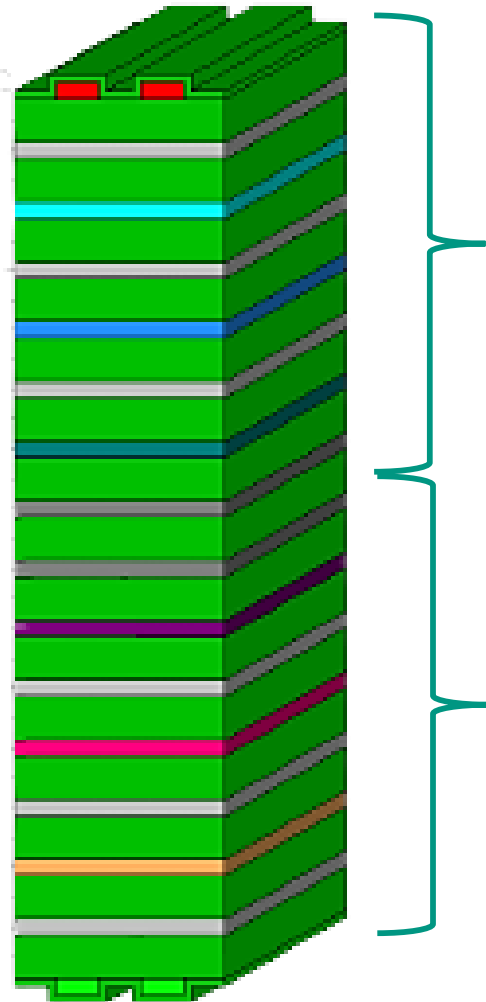


Digital Component Placement (Top)



PCB Design : Substrate & Metal Layer Stackup

Separate analog from digital:



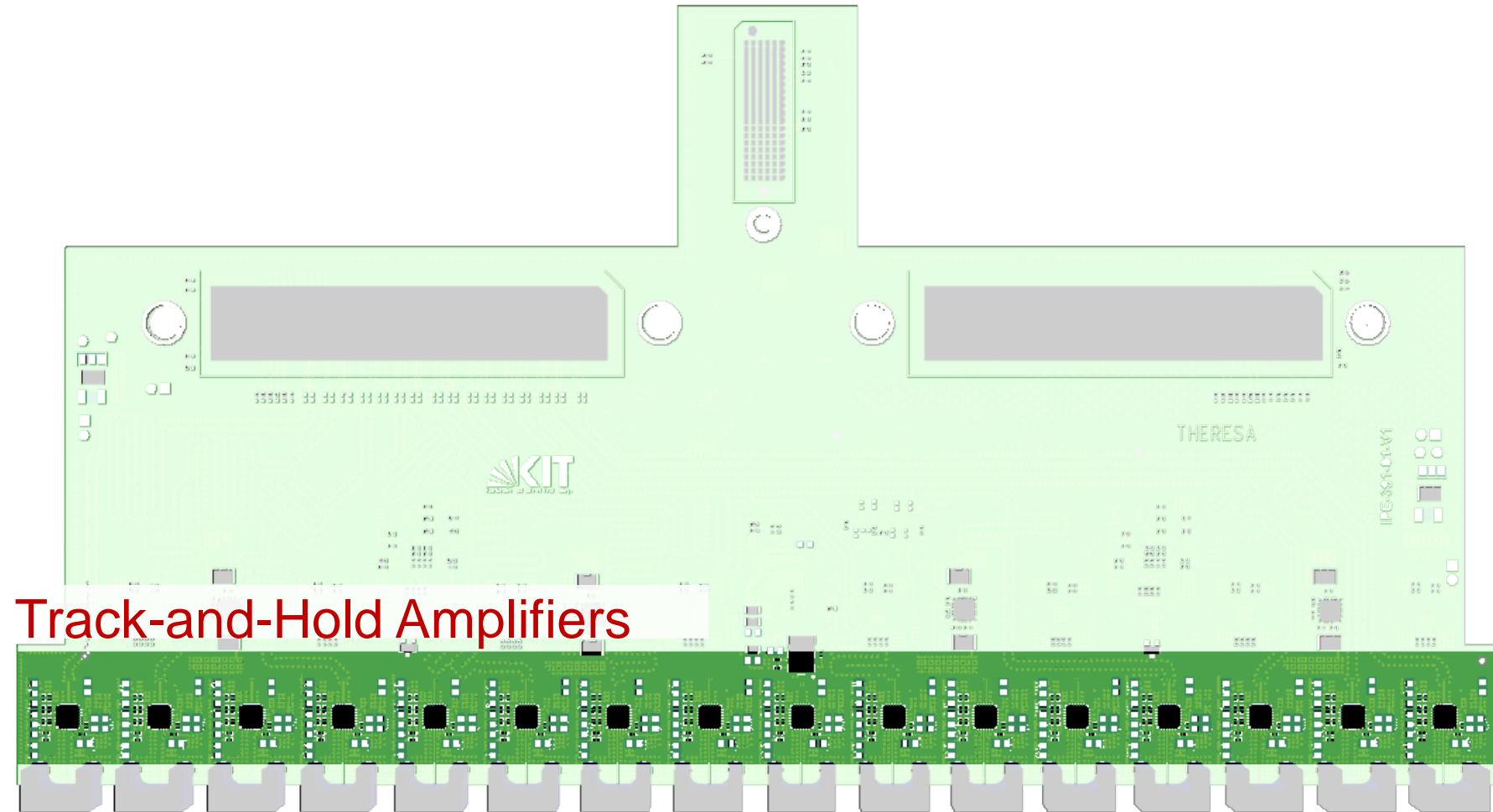
Digital part:

- Clocking distribution
- Delay chips
- Slow control lines

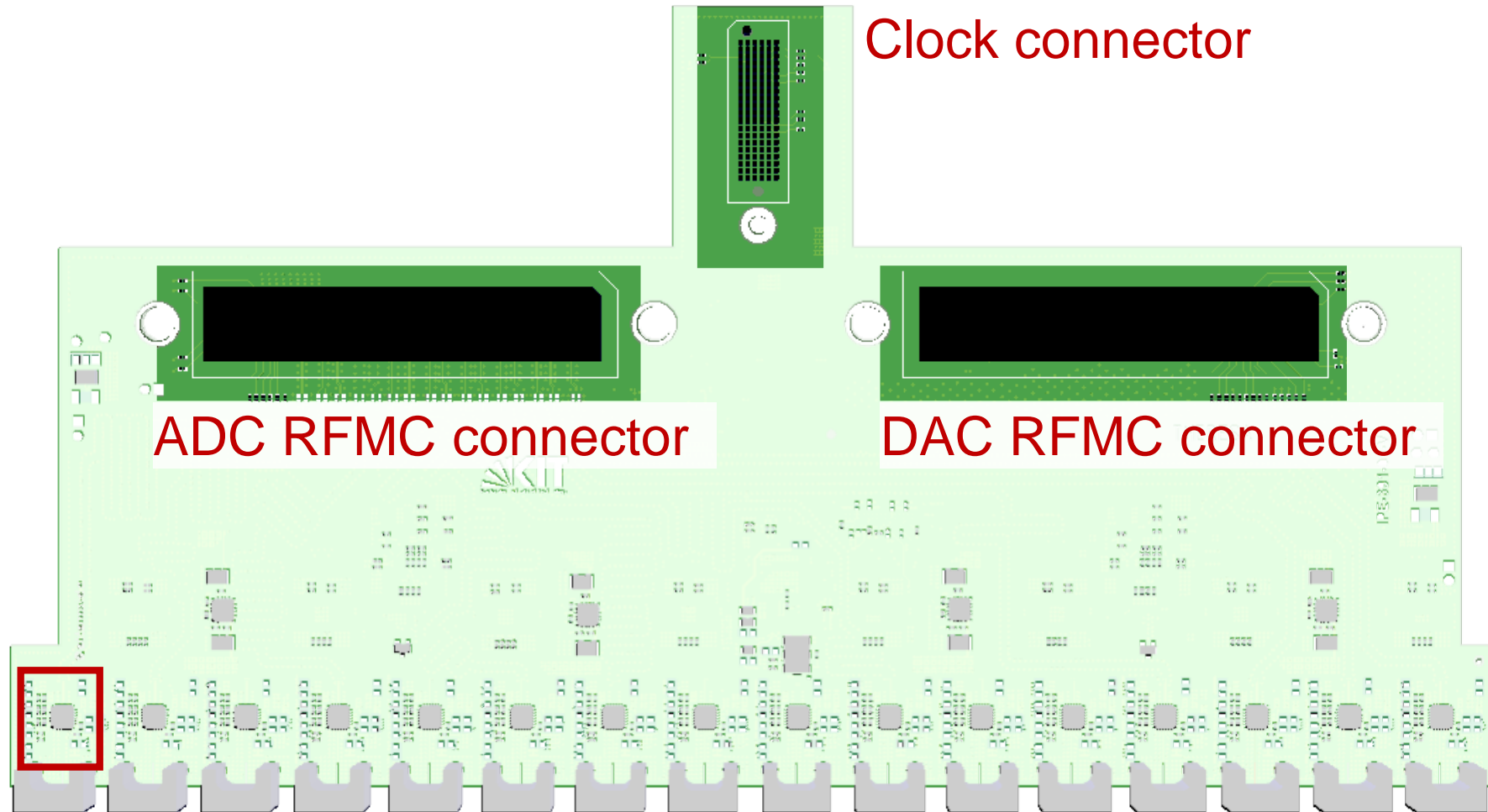
Analog part:

- Track-and-Hold amplifiers
- HF transmission lines
- Analog power supplies

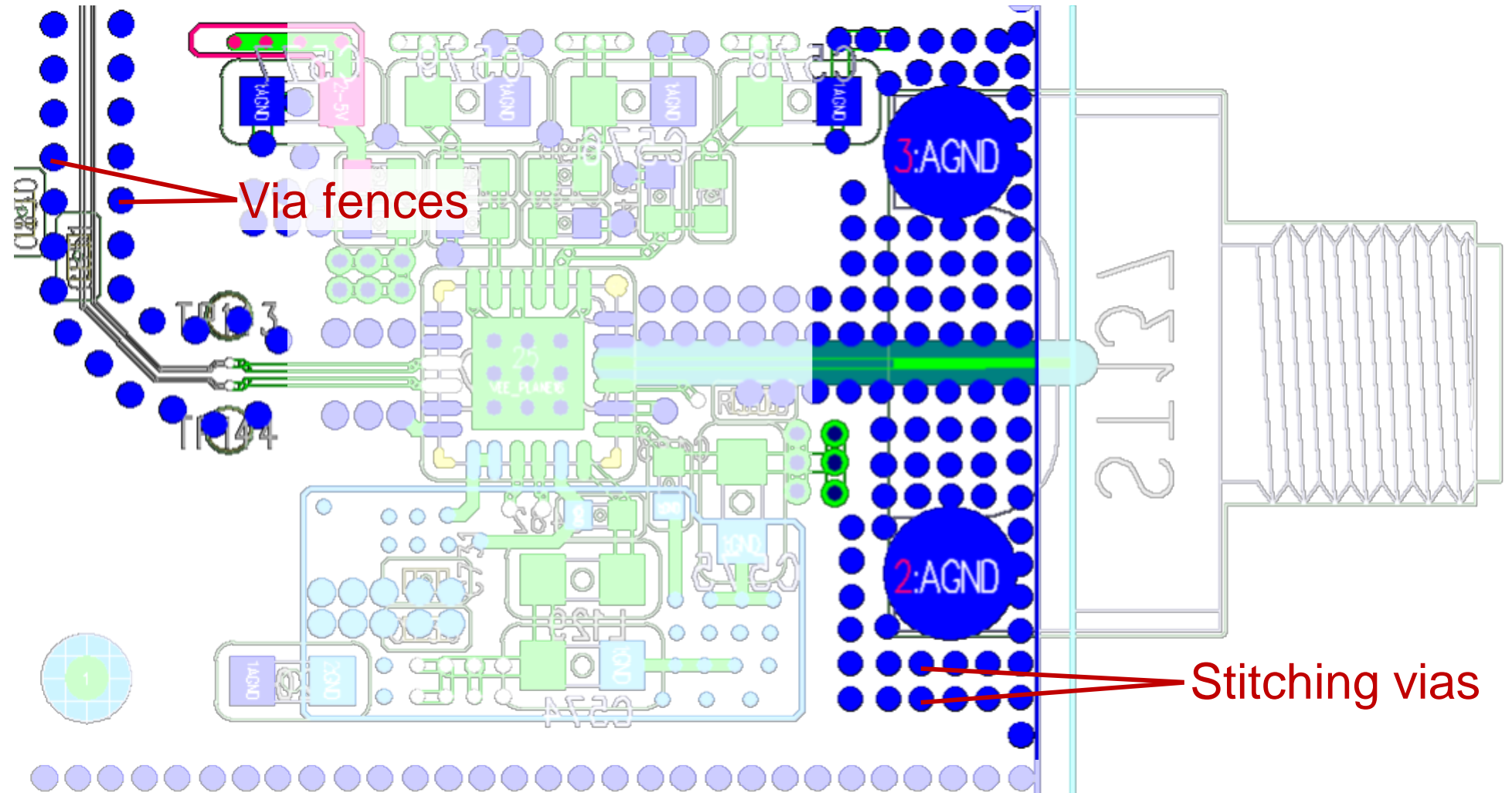
Analog Component Placement (Bottom)



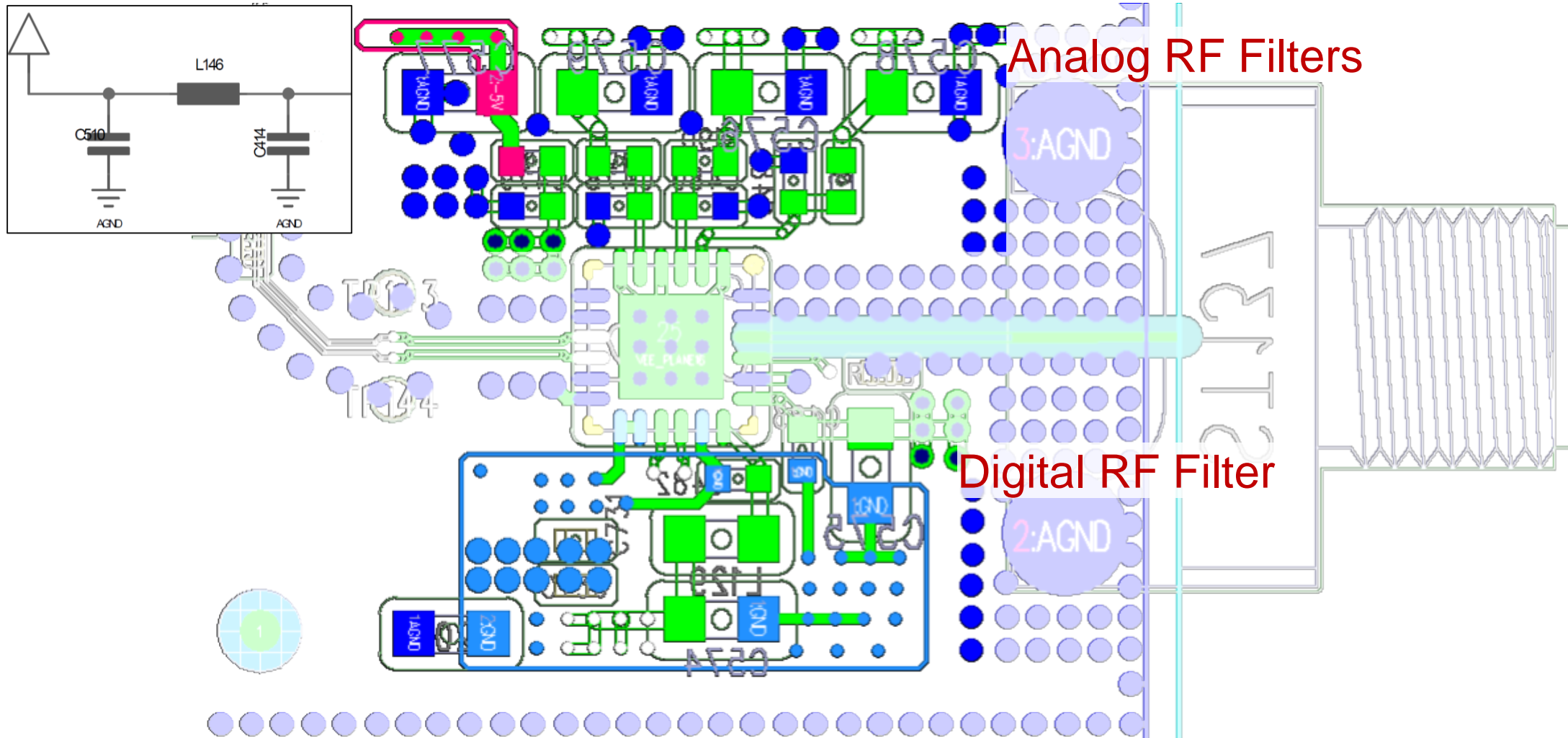
Analog Component Placement (Bottom)



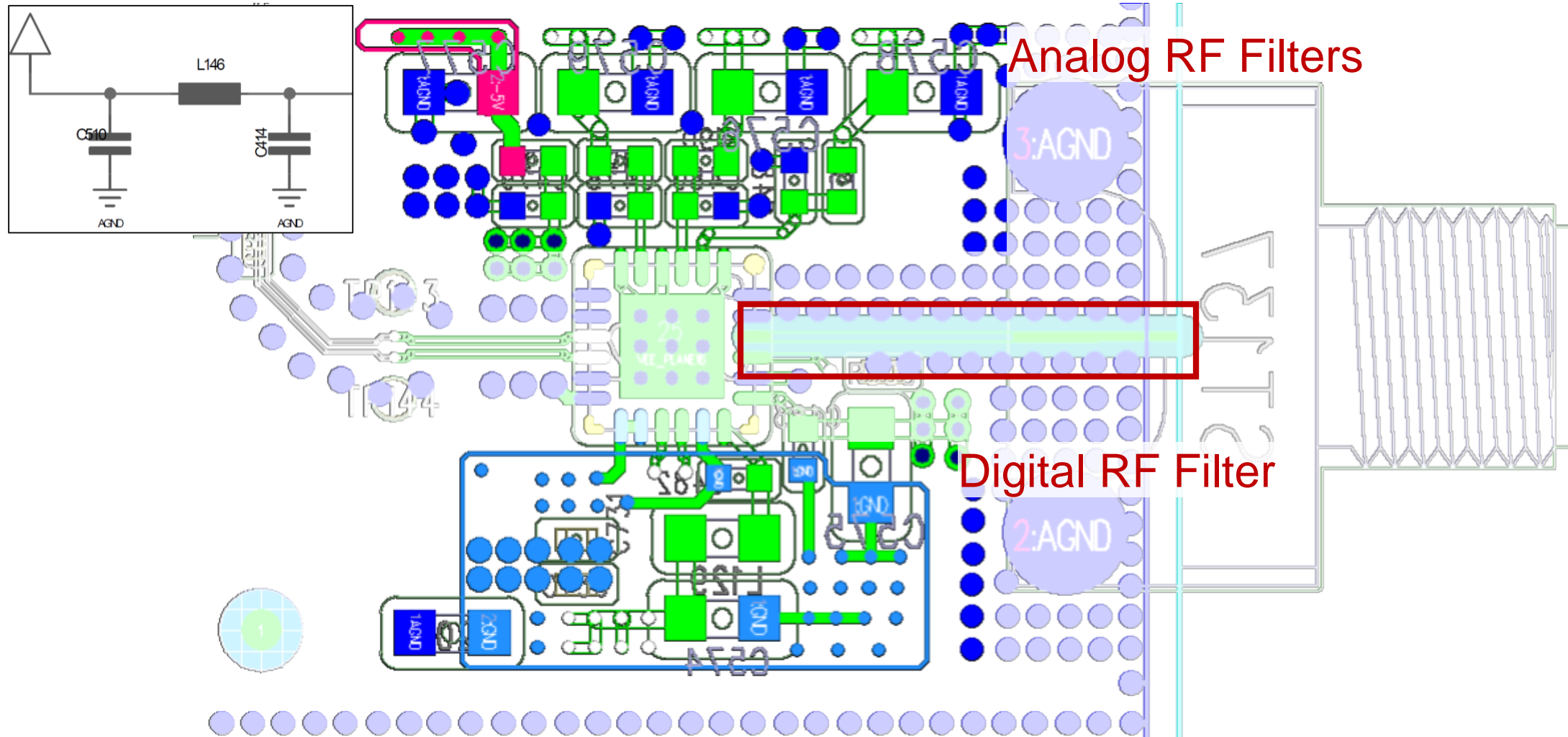
Design: Low Noise



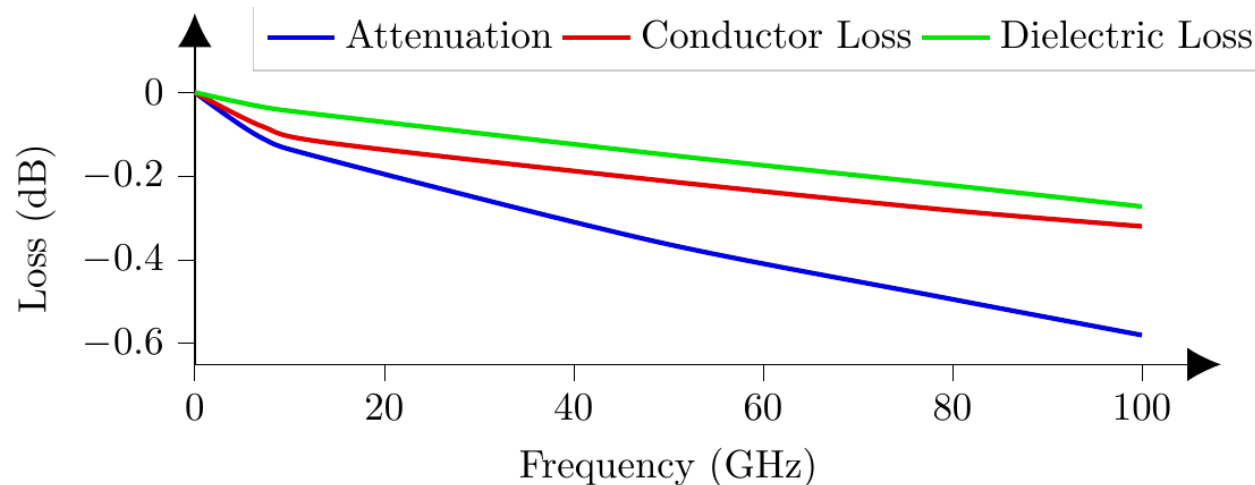
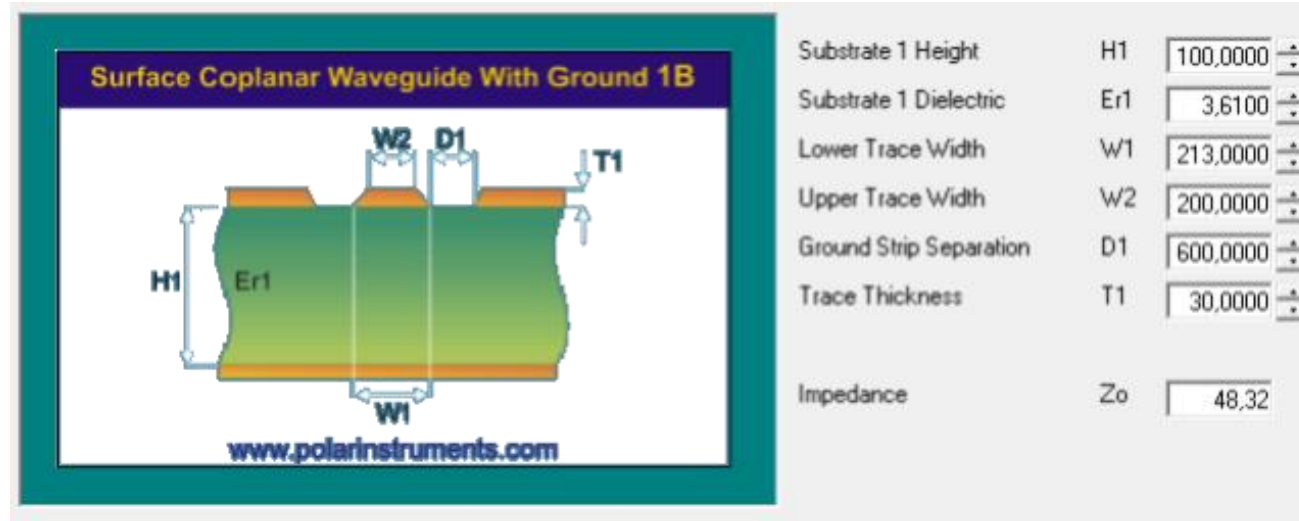
Design: Low Noise



Design: Low Noise



Design: Transmission Lines



$$Z_0 = \frac{60.0\pi}{\sqrt{\epsilon_{\text{eff}}}} \frac{1.0}{\frac{K(k)}{K(k')} + \frac{K(k_1)}{K(k'_1)}}$$

$$k = W1 / (2D1 + W1)$$

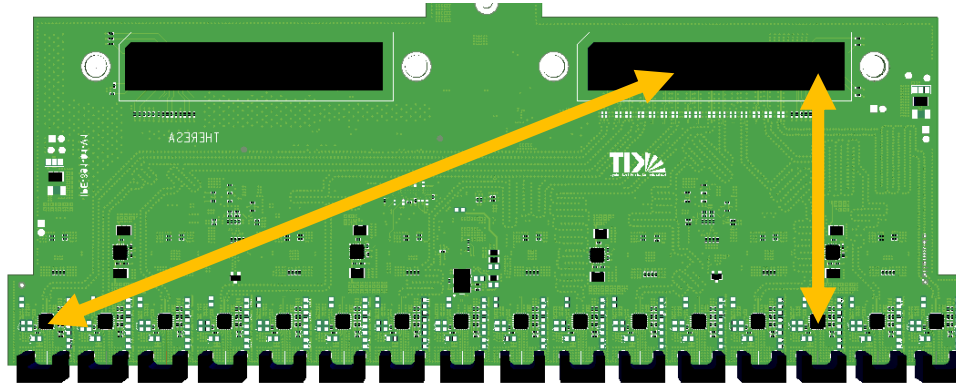
$$k' = \sqrt{1.0 - k^2}$$

$$k_1 = \frac{\tanh\left(\frac{\pi W1}{4.0 H1}\right)}{\tanh\left(\frac{\pi (2D1 + W1)}{4.0 H1}\right)}$$

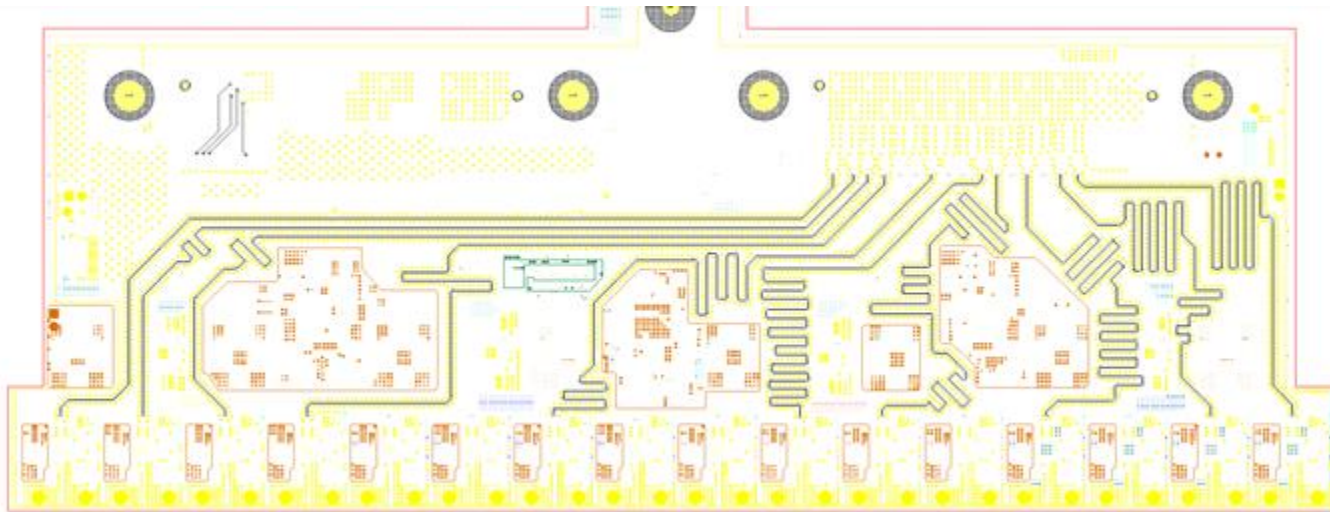
$$k'_1 = \sqrt{1.0 - k_1^2}$$

$$\epsilon_{\text{eff}} = \frac{1.0 + \epsilon_r \frac{K(k')}{K(k)} \frac{K(k_1)}{K(k'_1)}}{1.0 + \frac{K(k')}{K(k)} \frac{K(k_1)}{K(k'_1)}}$$

Design: Time Skew

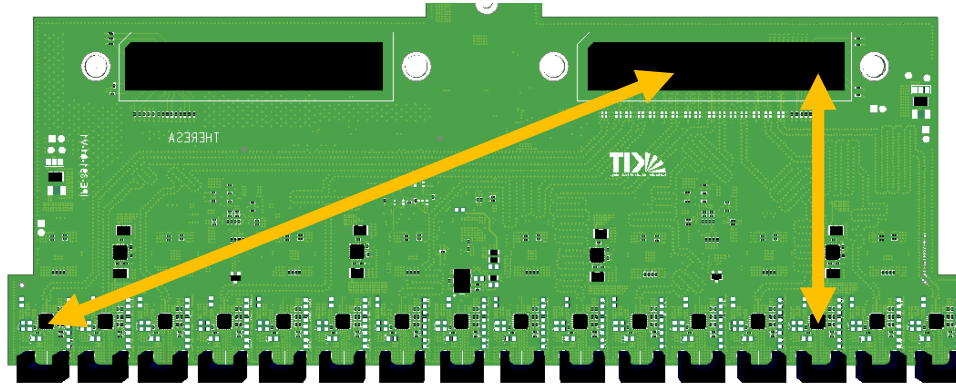


Signal path lengths differ
between THA_3 and THA_{16}



RF traces from
Track-and-Hold to RF-ADC
via RF-connector

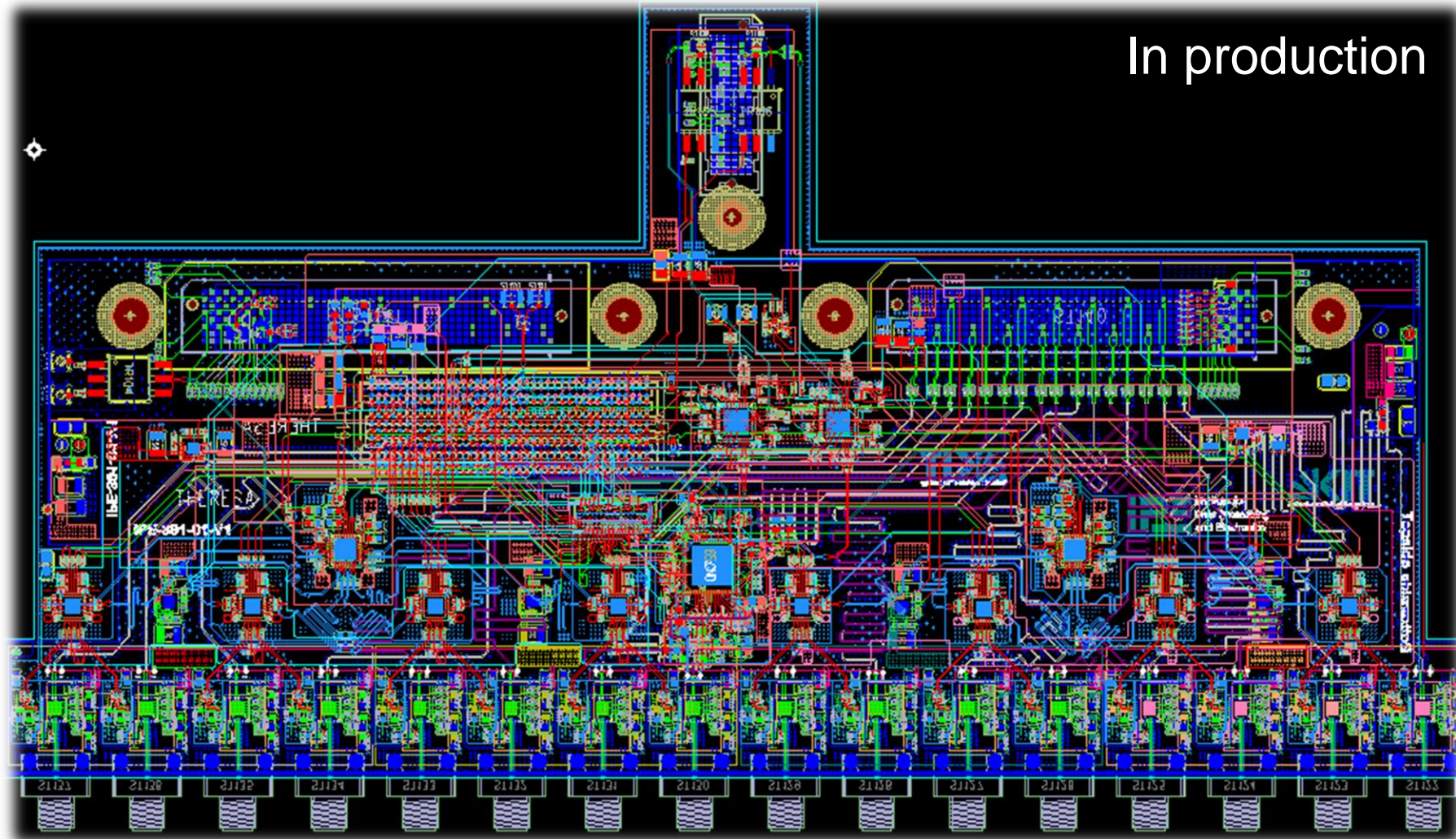
Design: Time Skew



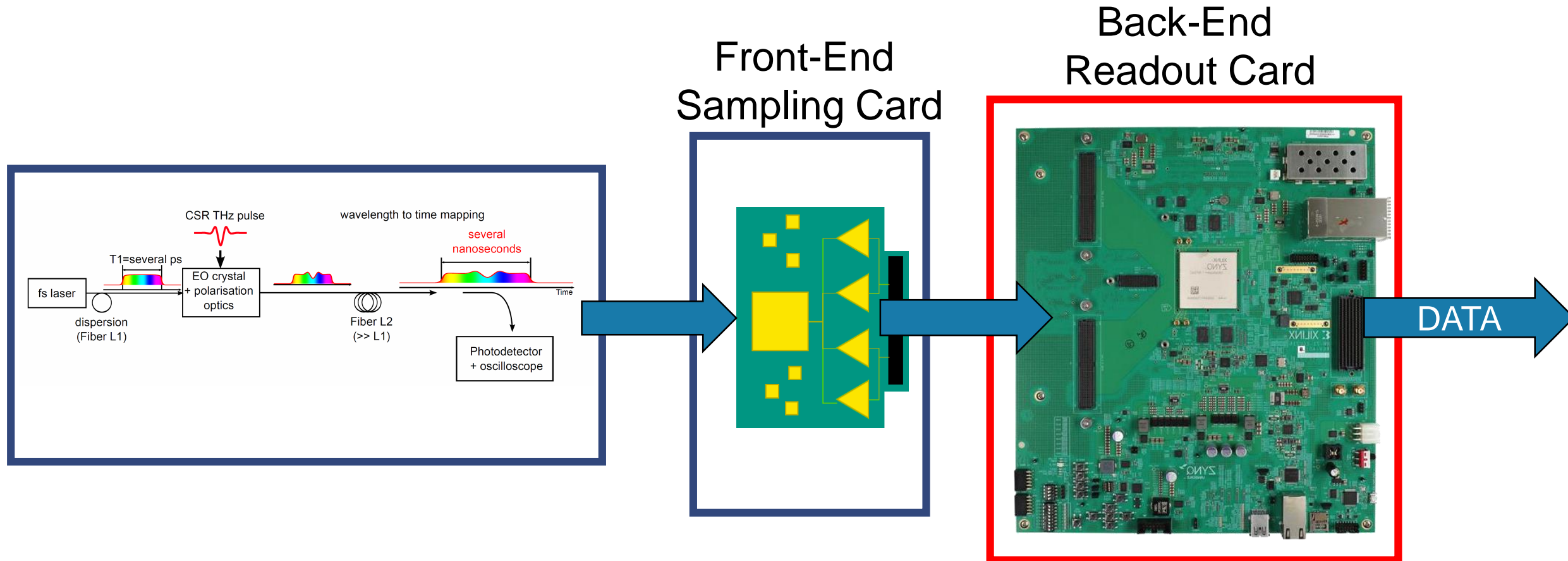
Signal path lengths differ between THA_3 and THA_{16}

Name	Estimated length	Routed length	Tolerance
OUT TH 1 P	197.35682	197.35682	1
OUT TH 2 N	197.48659	197.48659	1
OUT TH 2 P	197.58522	197.58522	1
OUT TH 3 N	197.44362	197.44362	1
OUT TH 3 P	197.42569	197.42569	1
OUT TH 4 N	197.4959	197.4959	1
OUT TH 4 P	197.49939	197.49939	1

Final PCB Layout

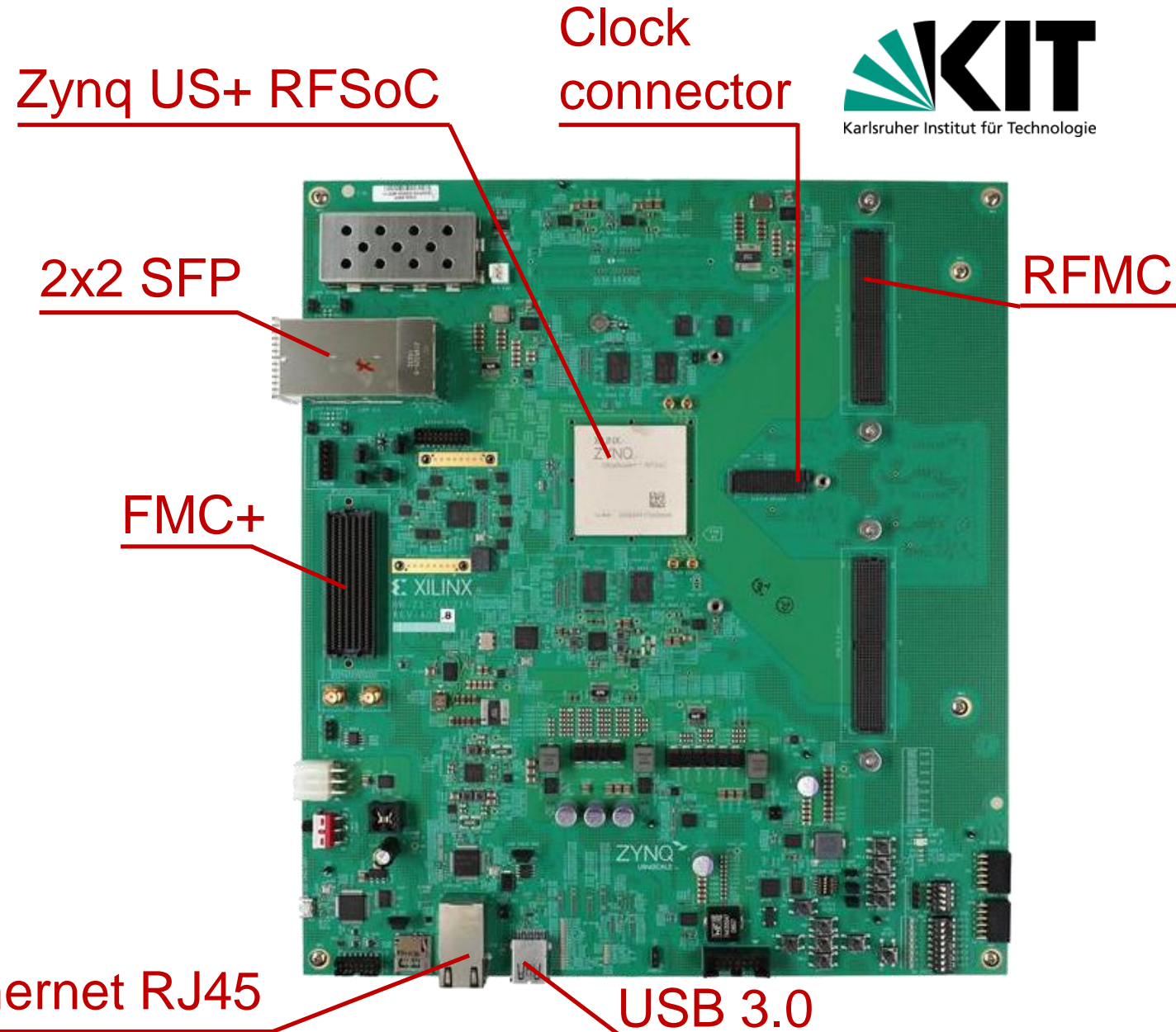


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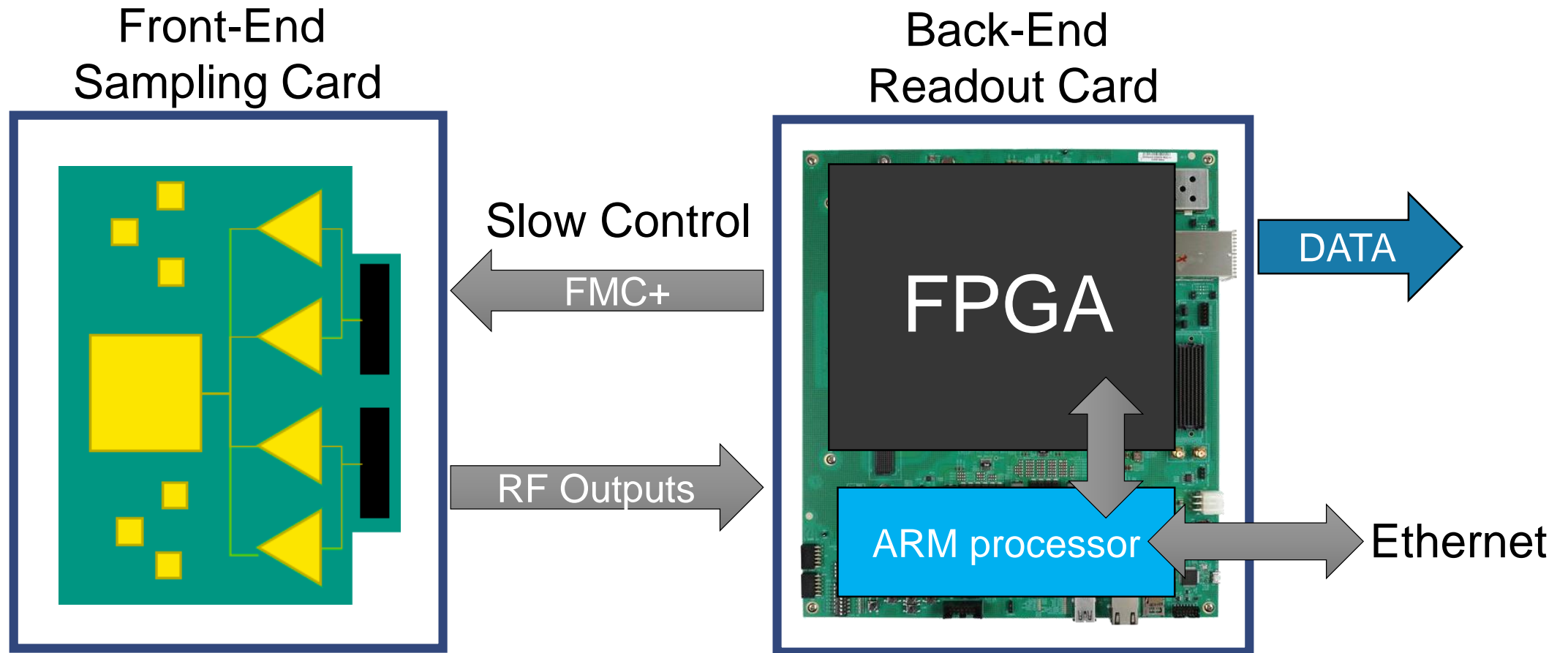


Back-End Readout Card

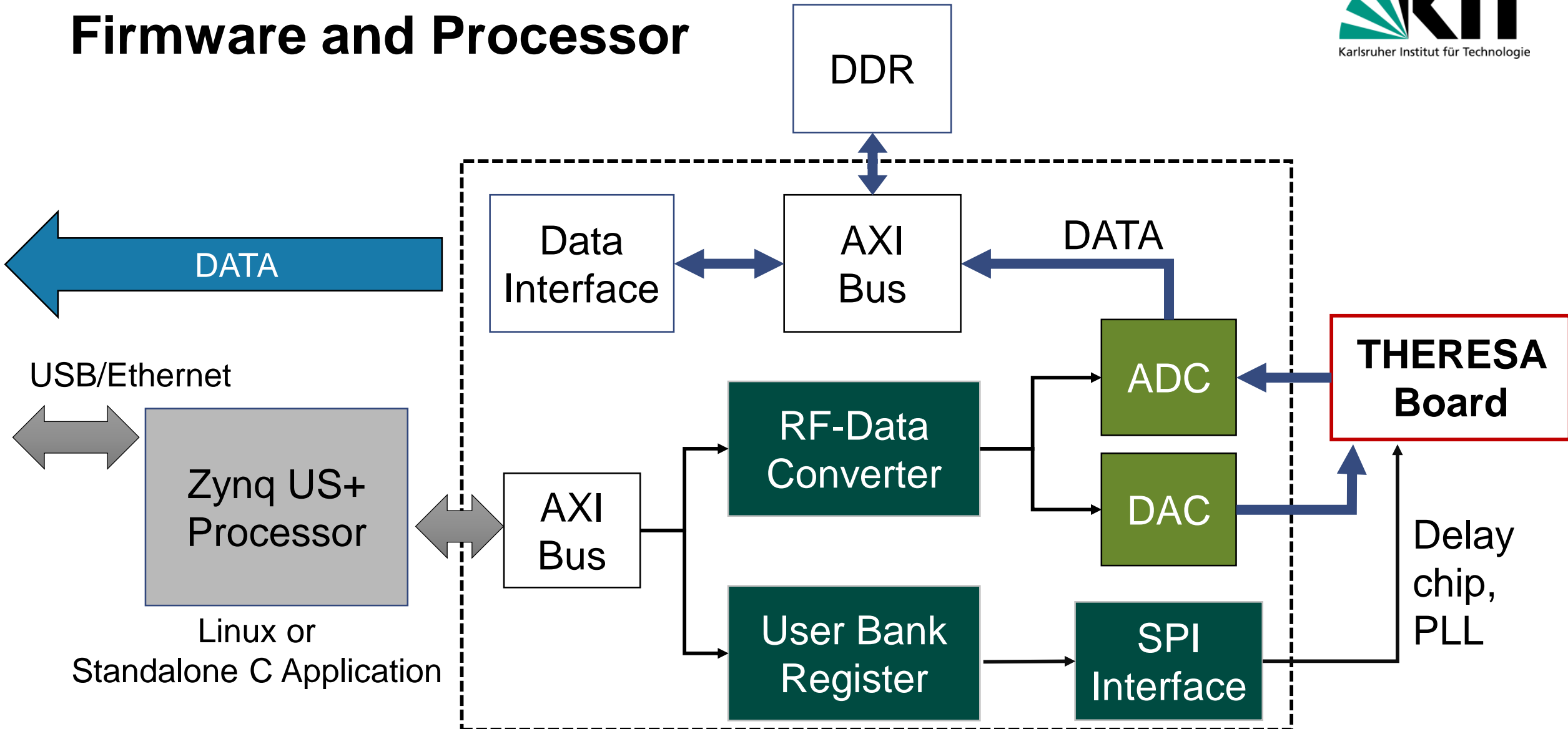
- Xilinx Evaluation Card (ZCU216)
- Zynq UltraScale+ RF-SoC
 - ARM CPU
 - FPGA
- 14-bit, 2.5 GSPS RF-ADC (16x)
- 14-bit, 10 GSPS RF-DAC (16x)
- 112 Gbps optical connections



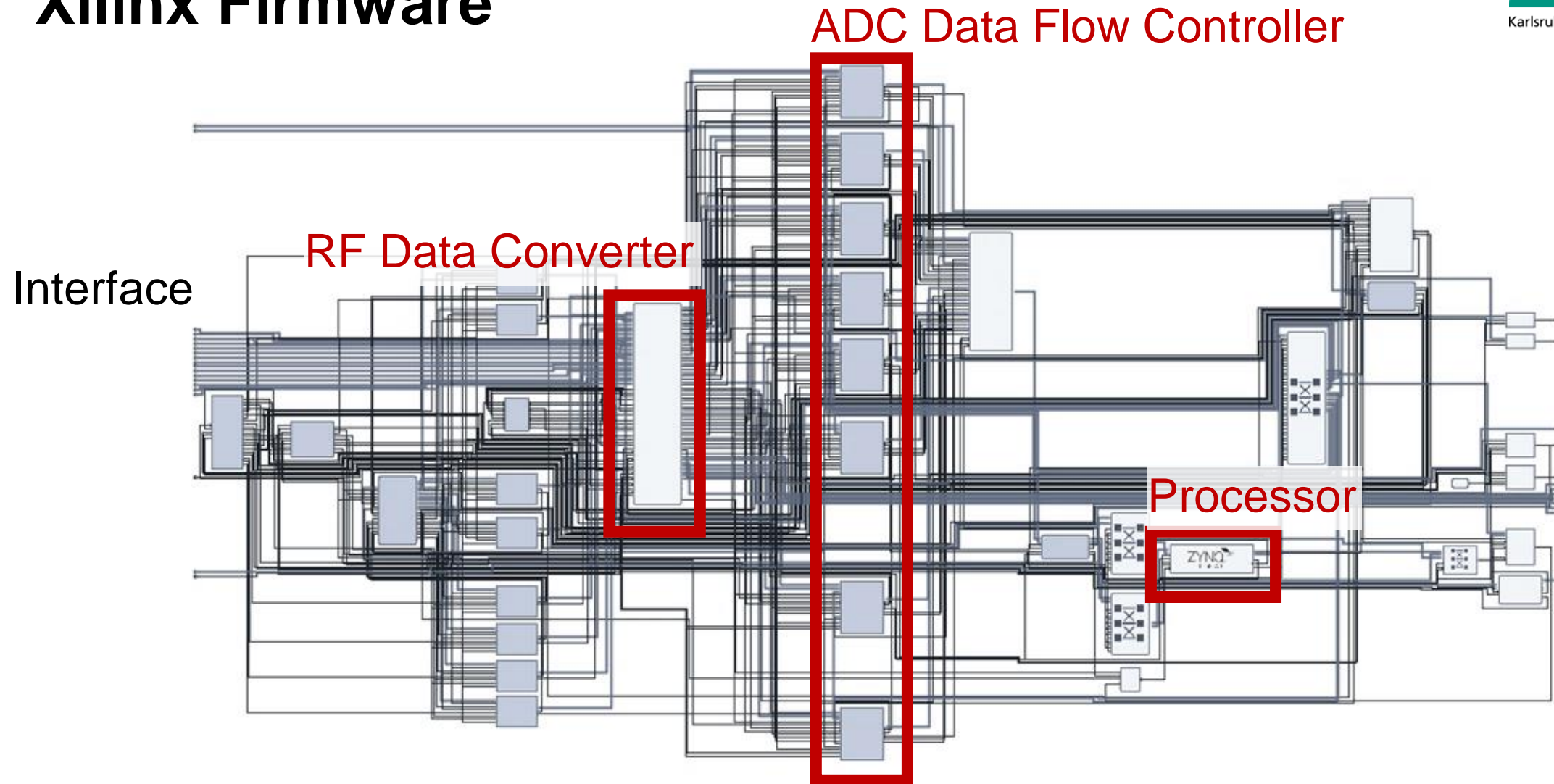
Firmware and Integration with ARM Processor



Firmware and Processor



Xilinx Firmware



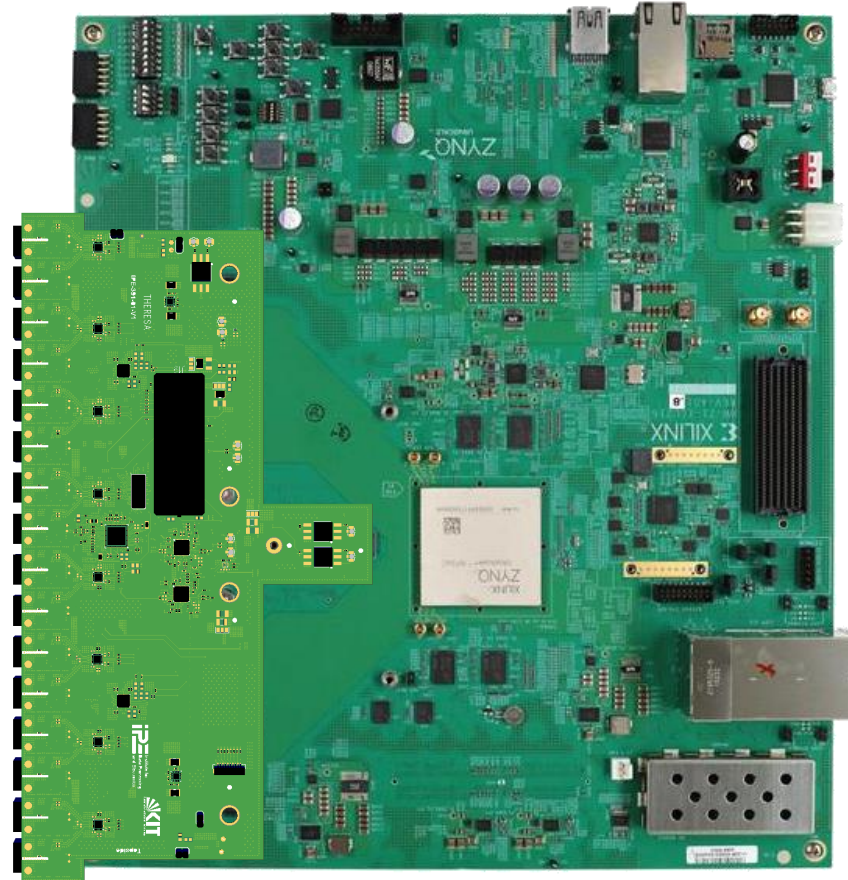
Results

- Front-end sampling card successfully designed
- Currently under production (ETA mid-Sept. 2021)
- Continuous sampling up to 40 GS/s
- Evaluation of a novel readout RF-SoC system + Xilinx Design Tool (Vitis)
- Firmware and slow-control developed

Conclusions & Outlook

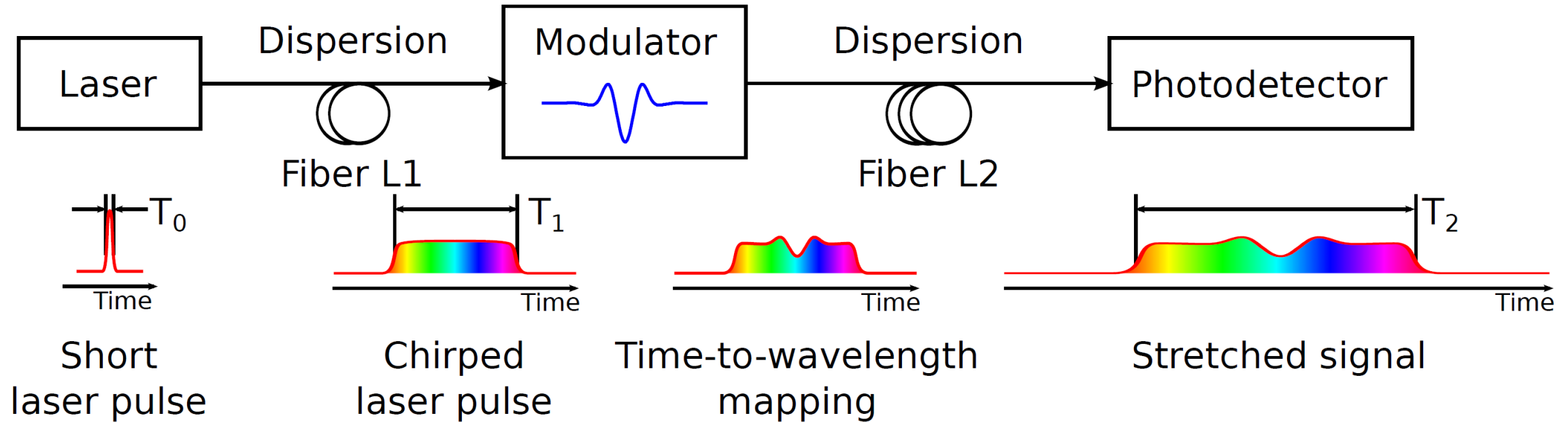
- THERESA is suitable for several applications at KARA
- DAQ infrastructure and firmware suitable for next generation of beam diagnostics instrumentations
- Selected FPGA is compatible with AI (i.e. Reinforcement-Learning) and interfacing with the BBB-feedback at KARA
- Characterization & integration with optical time-stretch setup in collaboration with Lille University
- Final commissioning at KARA

Thank you for your attention!



BACKUP

Photonic Time-Stretch Method



$$T_2 = M \cdot T_1$$

$$M = 1 + L2/L1$$

Example: $L1 = 10\text{m}$, $L2 = 2\text{km} \rightarrow M=200$

$T_1 = 1 \text{ ps} \triangleq 1 \text{ THz} \rightarrow T_2 = 200 \text{ ps} \triangleq 5 \text{ GHz}$

Table 117: RF-ADC Electrical Characteristics for ZU4xDR Devices

Parameter	Comments/Conditions ¹	Min	Typ ²	Max	Units
Analog inputs					
Resolution		14	–	–	Bits
Sample Rate	Devices using quad ADC tile channel	0.5	–	2.5	GS/s
	Devices using dual ADC tile channel	1	–	5	GS/s
Full-scale input	Input 100Ω on-die termination when DSA attenuation = 0 dB	–	1	–	V _{PPD}
		–	1	–	dBm
Maximum allowed input power	Input 100Ω on-die termination when DSA attenuation ≥ 15 dB	–	4.8	–	V _{PPD}
		–	14.6	–	dBm
Digital Attenuation Range		0	–	27	dB
Attenuator step size		–	1	–	dB
Auto attenuation	Automatically set when amplitude over-voltage is asserted	–	15	–	dB
Analog input bandwidth	Full-power bandwidth (–3 dB)	–	6	–	GHz
Return loss (R _L) ³	Up to 4 GHz	–	–12	–	dB
	Up to 6 GHz	–	–10	–	dB
Optimized common mode voltage range	Performance optimized range. AC and DC coupling modes ⁴	0.68	0.7	0.72	V
Maximum common mode voltage range	Available range before triggering over-voltage protection. AC and DC coupling modes ⁴	0.4	0.7	1	V
Crosstalk isolation between channels ⁵	F _{IN} = 0–4 GHz	–	–75	–	dBc
	F _{IN} = 0–6 GHz	–	–70	–	dBc

SFDR	Spurious free dynamic range excluding second- and third-order harmonic distortion, and including OIS and GTIS spurs.	$F_{IN} = 240 \text{ MHz}$	72.0	84.0	–	82.0	dBc
		$F_{IN} = 1.9 \text{ GHz}$	–	83.0	–	81.0	dBc
		$F_{IN} = 2.4 \text{ GHz}$	–	82.0	–	80.0	dBc
		$F_{IN} = 3.5 \text{ GHz}$	72.0	80.0	–	79.0	dBc
		$F_{IN} = 3.5 \text{ GHz, CW at } -10 \text{ dBFS}$	64.0	77.0	–	74.0	dBc
		$F_{IN} = 3.5 \text{ GHz, CW at } -20 \text{ dBFS}$	–	66.0	–	65.0	dBc
		$F_{IN} = 4.9 \text{ GHz}$	67.0	77.0	–	76.0	dBc
		$F_{IN} = 4.9 \text{ GHz, CW at } -10 \text{ dBFS}$	66.0	75.0	–	74.0	dBc
		$F_{IN} = 4.9 \text{ GHz, CW at } -20 \text{ dBFS}$	–	66.0	–	65.0	dBc
		$F_{IN} = 5.9 \text{ GHz}$	66.0	75.0	–	75.0	dBc
		$F_{IN} = 5.9 \text{ GHz, CW at } -10 \text{ dBFS}$	65.0	74.0	–	73.0	dBc
		$F_{IN} = 5.9 \text{ GHz, CW at } -20 \text{ dBFS}$	–	66.0	–	65.0	dBc

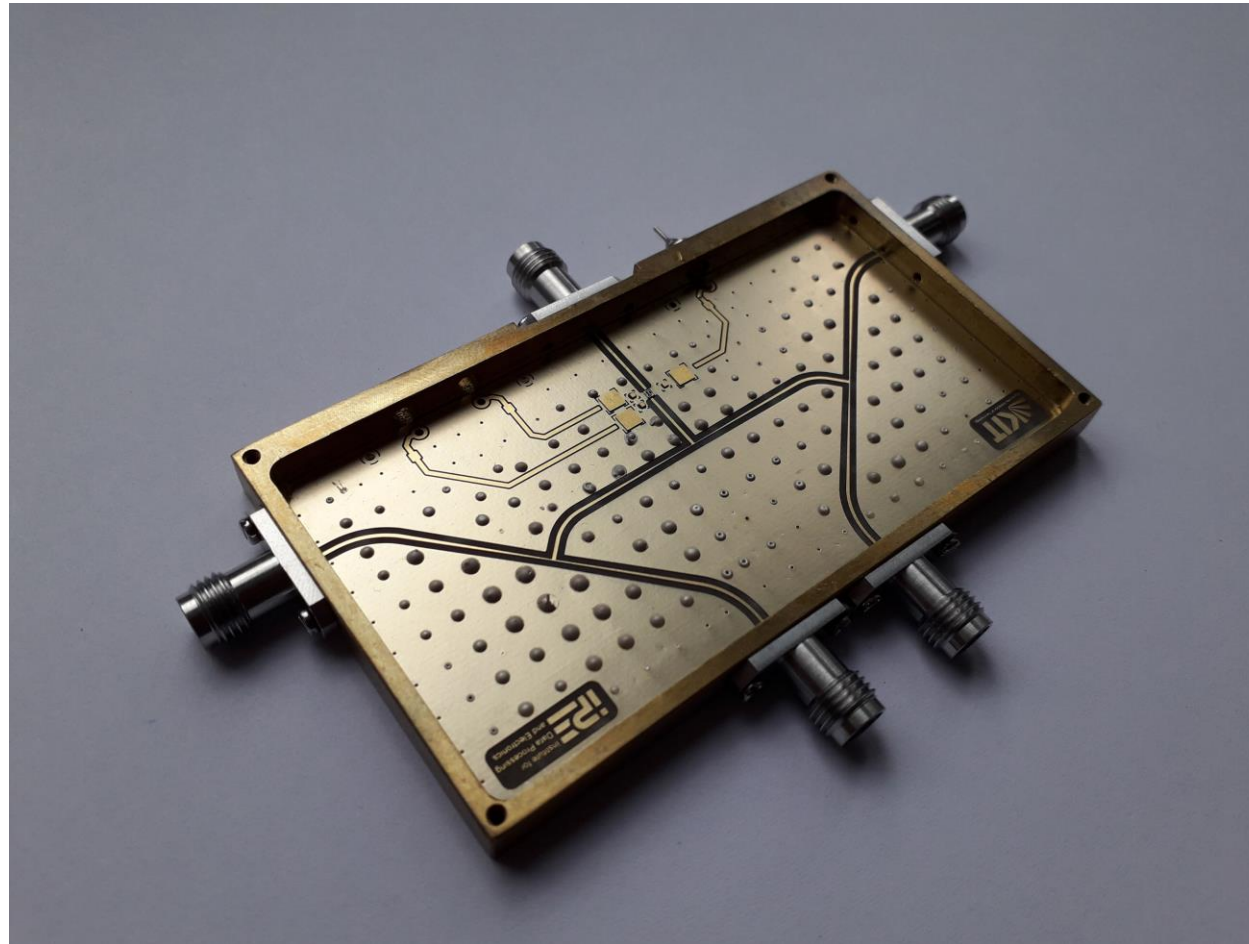
HMC5640BLC4B

DC - 18 GHz ULTRA-WIDEBAND, 4 GS/s TRACK-AND-HOLD AMPLIFIER

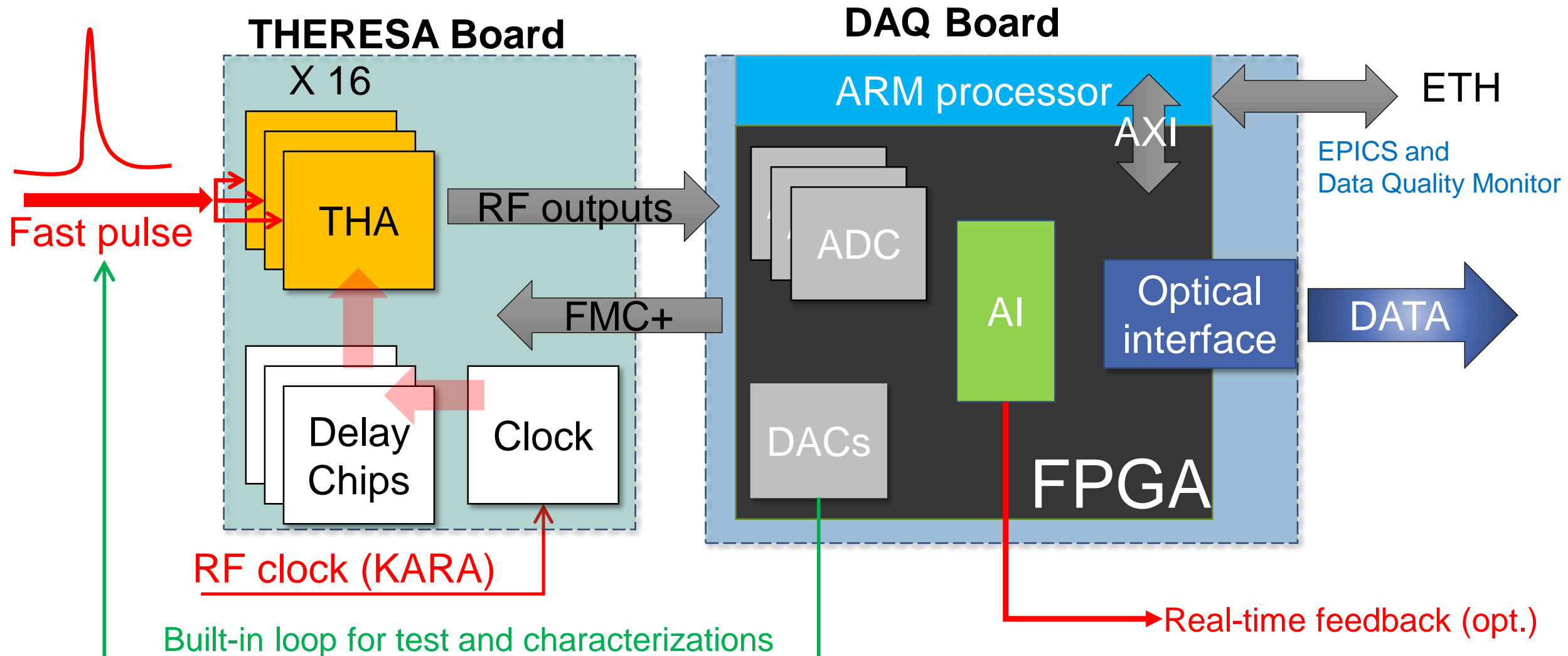
Features

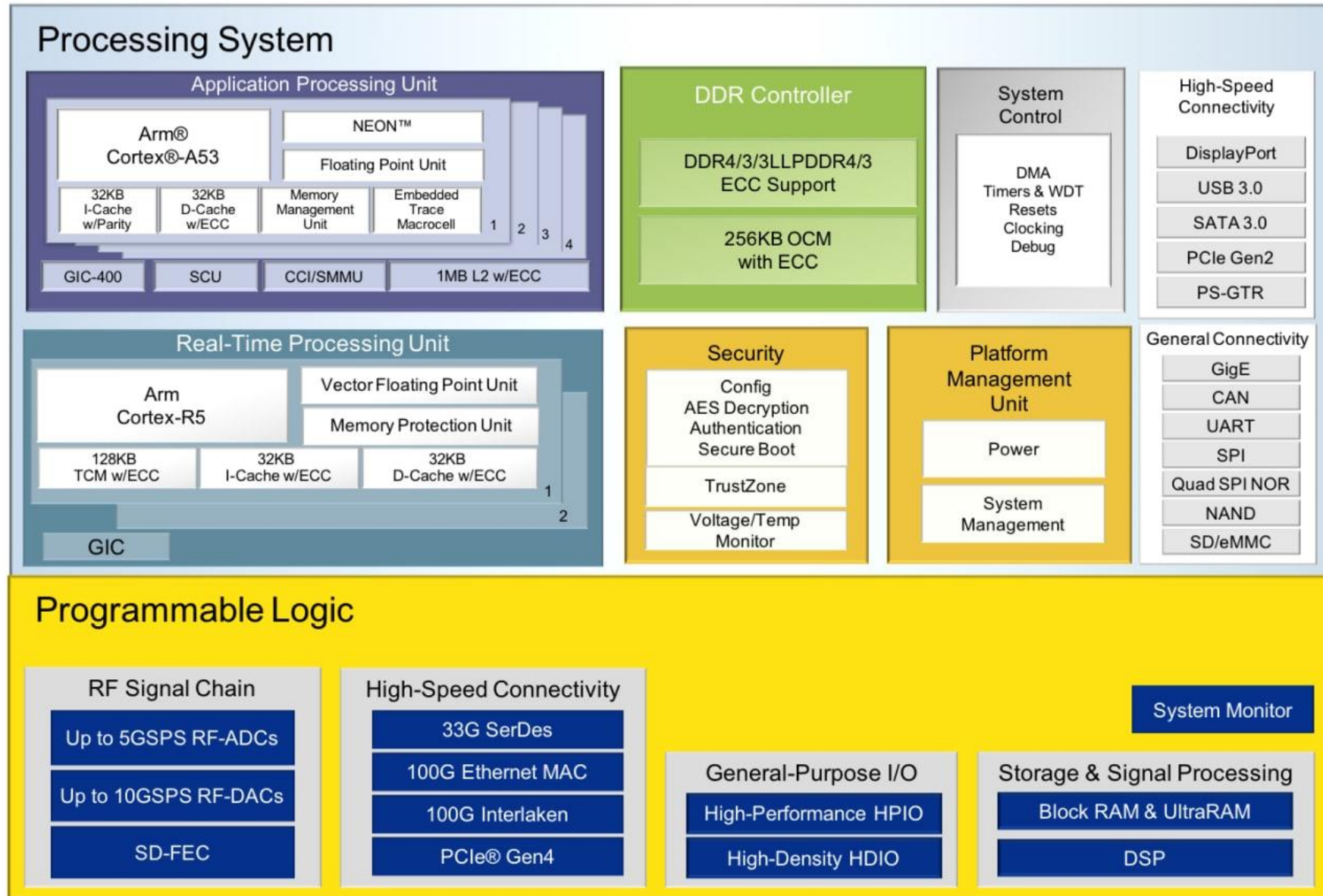
- 18 GHz Input bandwidth (1 Vp-p Full Scale)
- 4 GS/s Maximum Sampling Rate
- 68 dB SFDR (4 GHz / 0.5 Vp-p Input, CLK = 1 GS/s)
- 57 dB SFDR (4 GHz / 1 Vp-p Input, CLK = 1 GS/s)
- Direct-Coupled I/O
- Ultra-Clean Output Waveforms, Minimal Glitching
- >60 dB Hold Mode Feedthrough Rejection
- 1.05 mV RMS Hold Mode Output Noise
- Single / Dual Rank Evaluation Boards are Available
- RoHS Compliant 4x4 mm SMT Package

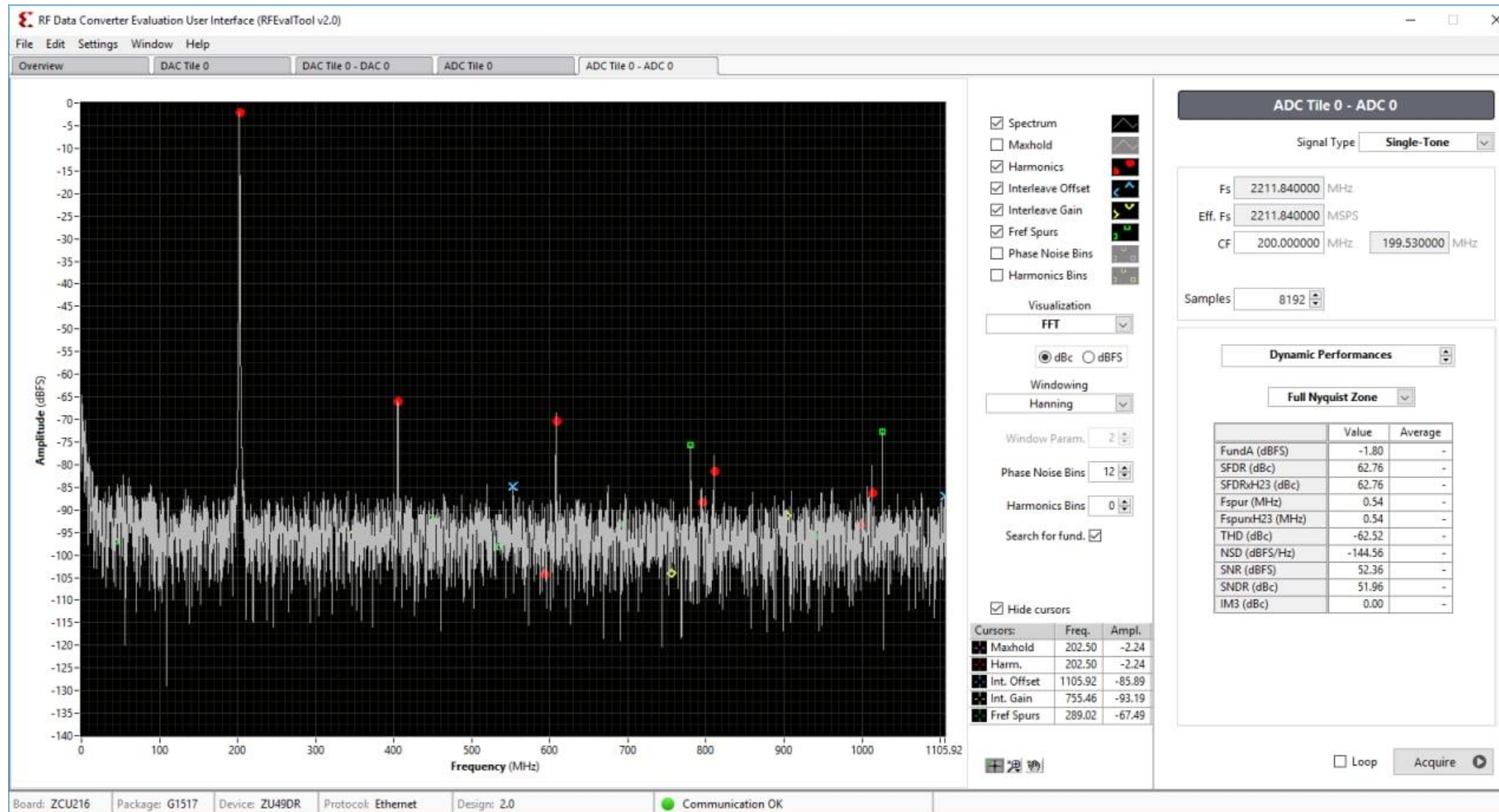
Backup slides



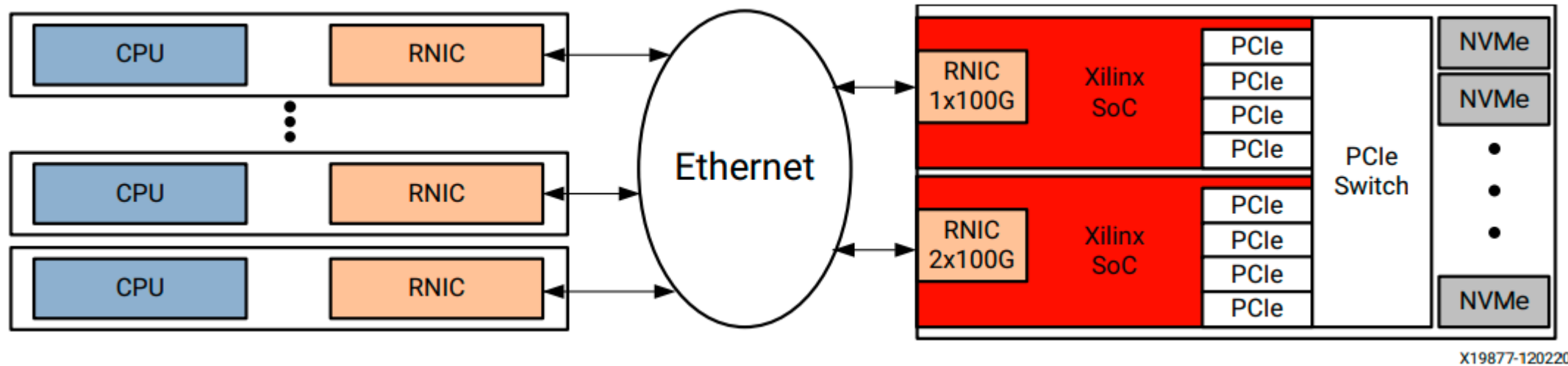
Back-End Readout Card (2)





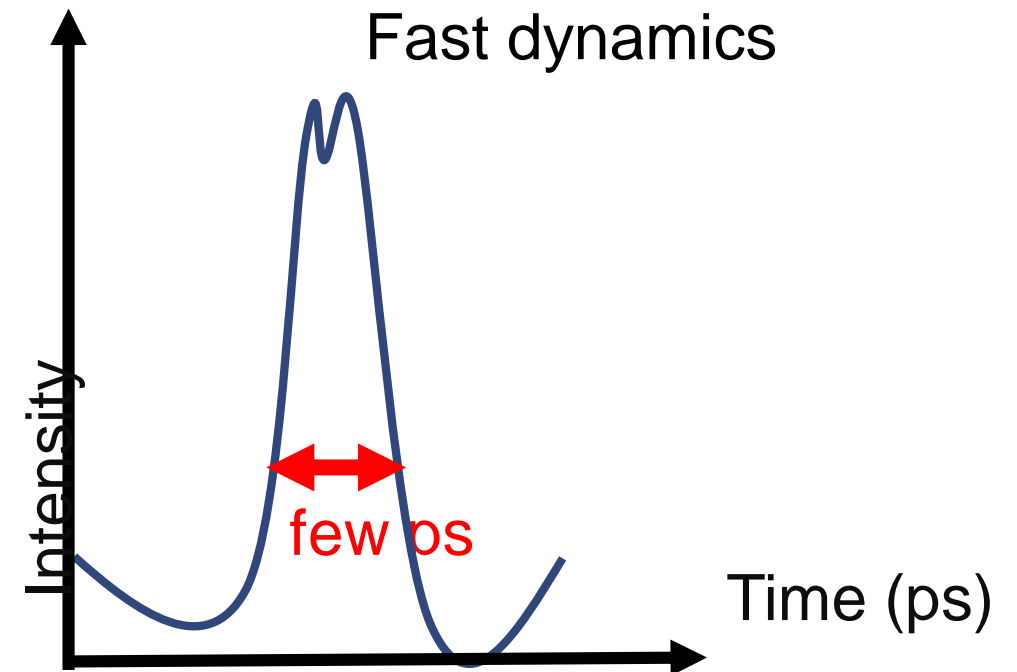


Backup slides



Backup slides

- Given: fs pulse
- Task: Measuring the pulse
- How to measure such a short pulse?
 - Requires sampling rate in THz range
 - Problem
- Idea/Solution: Photonic Time-Stretch



$$\text{ENOB} = \frac{\text{SINAD} - 1.76}{6.02}, \quad \text{SINAD} = \frac{P_{\text{signal}} + P_{\text{noise}} + P_{\text{distortion}}}{P_{\text{noise}} + P_{\text{distortion}}},$$